



EMC COMPLIANCE TEST REPORT

for

IPC

Trade Name : Advantech
Model Number : MBPC-400-XXXX (X=0-9, A-Z or Blank)
Serial Number : N/A
Report Number : 021389-E
Date : January 23, 2003
Regulations : See below

Standards	Results (Pass/Fail)
EN 55022: 1998 (Class A)	PASS
EN 55011:1998 (Group 1, Class A)	PASS
EN 61000-3-2: 1995 + A1: 1998 + A2: 1998 + A14: 2000	PASS
EN 61000-3-3: 1995	PASS
EN 55024: 1998	PASS
- IEC 61000-4-2: 2001	PASS
- IEC 61000-4-3: 1995	PASS
- IEC 61000-4-4: 1995	PASS
- IEC 61000-4-5: 1995	PASS
- IEC 61000-4-6: 1996	PASS
- IEC 61000-4-8: 1993	PASS
- IEC 61000-4-11: 1994	PASS

Prepared for:

Advantech Co., Ltd.

**No. 1, Alley 20, Lane 26, Rueiguang Road, Neihu District,
Taipei 114, Taiwan, R.O.C.**

Prepared by:

C&C LABORATORY, CO., LTD.

#B1, 1st Fl., Universal Center,

**No. 183, Sec. 1, Tatung Rd., Hsi Chih,
Taipei Hsien, Taiwan, R.O.C.**

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C&C Laboratory Co., Ltd.**

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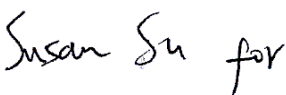
1 VERIFICATION OF COMPLIANCE

Equipment Under Test: IPC
Trade Name: Advantech
Model Number: MBPC-400-XXXX (X=0-9, A-Z or Blank)
Serial Number: N/A
Applicant: **Advantech Co., Ltd.**
No. 1, Alley 20, Lane 26, Rueiguang Road, Neihu District,
Taipei 114, Taiwan, R.O.C.
Manufacturer: **Advantech Co., Ltd.**
No. 1, Alley 20, Lane 26, Rueiguang Road, Neihu District,
Taipei 114, Taiwan, R.O.C.
Type of Test: EMC Directive 89/336/EEC for CE Marking
Technical Standards: EN 55022: 1998 (Class A)
EN 55011:1998 (Group 1, Class A)
EN 61000-3-2: 1995 + A1: 1998 + A2: 1998 + A14: 2000
EN 61000-3-3: 1995
EN 55024: 1998
(IEC 61000-4-2: 2001, IEC 61000-4-3: 1995, IEC 61000-4-4: 1995
IEC 61000-4-5: 1995, IEC 61000-4-6: 1996, IEC 61000-4-8: 1993
IEC 61000-4-11: 1994)
File Number: 021389-E
Date of Test: January 21 ~ 22, 2003
Deviation: According to applicant's declaration this EUT is a class A product, and to be
market in industrial environment only.
Condition of Test Sample: Normal
Final Result: Pass
Worst Data: See below

Test Item	Freq. (MHz)	Measured Data	Margin (M _i C)	Remark
Radiated Emission	336.03	42.6 (dB/m)	-4.4 dB (± 3.3308 dB)	
Conducted Emission	0.150	51.3 (dB)	-27.7 dB (± 2.8104 dB)	
<ul style="list-style-type: none">● The negative sign in Margin cell means under the specific limit.● This test result traceable to national or international standards.				

The above equipment was tested by C&C Laboratory Co., Ltd. for compliance with the requirements set forth in EMC Directive 89/336/EEC and the Technical Standards mentioned above. This said equipment in the configuration described in this report shows the maximum emission levels emanating from equipment and the level of the immunity endurance of the equipment are within the compliance requirements.

The test results of this report relate only to the tested sample identified in this report.

Approved by Authorized Signatory: 
Jonson Lee / EMC Director

2 GENERAL INFORMATION

Applicant: Advantech Co., Ltd.
No. 1, Alley 20, Lane 26, Rueiguang Road, Neihu District,
Taipei 114, Taiwan, R.O.C.

Contact Person: John Chou

Manufacturer: Advantech Co., Ltd.
No. 1, Alley 20, Lane 26, Rueiguang Road, Neihu District,
Taipei 114, Taiwan, R.O.C.

File Number: 021389-E

Date of Test: January 21 ~ 22, 2003

Equipment Under Test: IPC

Model Number: MBPC-400-XXXX (X=0-9, A-Z or Blank)

Serial Number: N/A

Type of Test: EMC Directive 89/336/EEC for CE Marking

Technical Standards: EN 55022: 1998 (Class A)
EN 55011:1998 (Group 1, Class A)
EN 61000-3-2: 1995 + A1: 1998 + A2: 1998 + A14: 2000
EN 61000-3-3: 1995
EN 55024: 1998
(IEC 61000-4-2: 2001, IEC 61000-4-3: 1995, IEC 61000-4-4: 1995
IEC 61000-4-5: 1995, IEC 61000-4-6: 1996, IEC 61000-4-8: 1993
IEC 61000-4-11: 1994)

**Frequency Range
(EN 55022):** 150kHz to 30MHz for Line Conducted Test
30MHz to 1000MHz for Radiated Emission Test

Test Site C&C LABORATORY CO., LTD.
No. 81-1, 210 Lane, Pa-de 2nd Road, Lu-Chu Hsiang
Taoyuan, Taiwan, R. O. C.

3 SYSTEM DESCRIPTION

EUT Test Program:

1. An EMI test software was loaded and executed ' Windows 2000' mode.
2. A communicated software was loaded and executed to communicate between EUT and remote side.
3. EUT (Industrial PC) sends and receives data from Notebook PC on remote side via LAN cable.
4. Data was sent to monitor filling the screen with upper case of "H" patterns.
5. Test program sequentially exercised all related I/O's of EUT and sent "H" patterns to all applicable output ports of EUT.
6. Repeat 3 to 5. Test program is self-repeating throughout the test.

4 PRODUCT INFORMATION

Housing Type:	Metal Case		
EUT Power Rating:	100-250 VAC, 60-50Hz, 3A		
AC Power during Test:	230VAC/50Hz		
Power Supply Manufacturer:	Skynet	Model:	SNP-8086
AC Power Cord Type:	Unshielded, 1.8m (Detachable)		
CPU Board Manufacturer:	Intel	Model:	PIII 1.266MHz
OSC/Clock Frequencies:	133MHz		
Memory Capacity:		Install:	128MB
HDD Manufacturer:	IBM	Model:	DARA-20600
Main Board Manufacturer:	Advantech	Model:	MBPC-4000-9575 MBPC-4000-9577
Chassis Manufacturer:	Advantech	Model:	MBPC-4000
LAN Card:	On Board		

I/O Port of EUT

I/O PORT TYPES	Q' TY	TESTED WITH
1). Parallel Port	1	1
2). Serial Port	4	4
3). PS/2 Keyboard Port	1	1
4). PS/2 Mouse Port	1	1
5). Video Port	1	1
6). Audio In Port	3	3
7). Audio Out Port	1	1
8). LAN Port	1	1
9). USB Port	2	2

- Note:**
1. The means of suffix "XXXX" (X=0~9, A-Z or Blank) on model number, just for mainboard difference. (Please refer to photo on this report).
 2. Client consigns only two model samples to test (Model Number: MBPC-400-9575, MBPC-400-9577). Therefore, the testing Lab. just guarantees the units, which have been tested..

5 SUPPORT EQUIPMENT

No.	Equipment	Model #	Serial #	FCC ID	Trade Name	Data Cable	Power Cord
1.	Monitor	CPD-G200	2715863	FCC DoC	Sony	Shielded, 1.8m with a core	Unshielded, 1.8m
2.	Modem	231AA	A25531083541	BFJ9D93108US	Hayes	Shielded, 1.8m	Unshielded, 1.8m
3.	Modem	2400	94-364-176268	BF9D93108US	Hayes	Shielded, 1.8m	Unshielded, 1.8m
4.	Printer	2225C	2648S40021	DK467GSM24	HP	Shielded, 1.8m	Unshielded, 1.8m
5.	PS/2 Keyboard	SK-2800C	B1C790BCPJ73JM	GYUR79SK	Compaq	Shielded, 1.8m	N/A
6.	PS/2 Mouse	M-CAA43	LZE02801285	FCC DoC	Logitech	Shielded, 1.8m	N/A
7.	Mouse	M-MM43	LZE93352988	FCC DoC	Logitech	Shielded, 1.8m	N/A
8.	Mouse	M-MM43	LZE94052771	FCC DoC	Logitech	Shielded, 1.8m	N/A
9.	USB Mouse	M-BB48	LZE01450904	FCC DoC	Logitech	Shielded, 1.8m	N/A
10.	USB Mouse	M-BB48	LZE01361333	FCC DoC	Logitech	Shielded, 1.8m	N/A
11.	Earphone	GT-2004V	N/A	N/A	GITON	Unshielded, 1.2m	N/A
12.	Microphone	DM-510	N/A	N/A	KOKA	Unshielded, 2.2m	N/A
13.	Microphone	DM-510	N/A	N/A	KOKA	Unshielded, 2.2m	N/A
14.	Microphone	DM-510	N/A	N/A	KOKA	Unshielded, 2.2m	N/A
15.	Notebook PC (Remote)	M285	NU2503544	FCC DoC	LEO	LAN Cable: Unshielded, 10m	AC I/P: Unshielded, 1.8m DC O/P: Unshielded, 1.8m with a core

Note: All the above equipment/cables were placed in worse case positions to maximize emission signals during emission test.

Grounding: Grounding was in accordance with the manufacturer's requirements and conditions for the intended use.

6 TEST FACILITY

- Location:** No. 81-1, 210 Lane, Pa-de 2nd Road, Lu-Chu Hsiang, Taoyuan, Taiwan, R. O. C.
- Description:** There are four 3/10m open area test sites and three line conducted labs for final test. The Open Area Test Sites and the Line Conducted labs are constructed and calibrated to meet the FCC requirements in documents ANSI C63.4: 1992 and CISPR 16 requirements.
- Site Filing:** A site description is on file with the Federal Communications Commission, 7435 Oakland Mills Road, Columbia, MD 21046.
- Registration also was made with Voluntary Control Council for Interference (VCCI).
- Site Accreditation:** Accredited by NEMKO (Authorization #: ELA 124) for EMC & A2LA (Certificate #: 824.01) for Emission
- Also accredited by BSMI for the product category of Information Technology Equipment.
- Instrument Tolerance:** All measuring equipment is in accord with ANSI C63.4 and CISPR 22 requirements that meet industry regulatory agency and accreditation agency requirement.
- Ground Plane:** Two conductive reference ground planes were used during the Line Conducted Emission, one in vertical and the other in horizontal. The dimensions of these ground planes are as below. The vertical ground plane was placed distancing 40 cm to the rear of the wooden test table on where the EUT and the support equipment were placed during test. The horizontal ground plane projected 50 cm beyond the footprint of the EUT system and distanced 80 cm to the wooden test table. For Radiated Emission Test, one horizontal conductive ground plane extended at least 1m beyond the periphery of the EUT and the largest measuring antenna, and covered the entire area between the EUT and the antenna. It has no holes or gaps having longitudinal dimensions larger than one-tenth of a wavelength at the highest frequency of measurement up to 1GHz.

Site # 3 & # 4 Line Conducted Test Site: At Shielding Room

FEDERAL COMMUNICATIONS COMMISSION
Laboratory Division
3433 Oakland Mills Road
Columbia, MD 21046

March 06, 2003

Registration Number: 80004

C & C Laboratory Co., Ltd.
No. 81-1, 210 Lane,
Feng-2nd Road, La-Cha-Hsiang
Taoyuan
Taiwan
Attention: Kurt Chen

Re: Measurement facility located at Taoyuan
Site No. 417 & 10 (interior)
Date of Listing: March 06, 2003

Confirmation:

Your submission of the description of the subject measurement facility has been reviewed and found to be in compliance with the requirements of Section 2.944 of the FCC Rules. The description has, therefore, been placed on the web site of your organization added to the Commission's list of facilities whose measurement data will be accepted in conjunction with applications for Certification under Parts 17 or 18 of the Commission's Rules. Please note that this listing must be updated for any changes made to the facility, and at least every three years from the date of listing the data on file must be certified as current.

If requested, the above mentioned facility has been added to our list of those who perform these measurement services for the public on a fee basis. An up-to-date list of such public test facilities is available on the Internet on the FCC Website at WWW.FCC.GOV, E-File, MET Equipment Authorization Electronic Filing.

Sincerely,

Thomas W. Phillips
Director/Engineer

FEDERAL COMMUNICATIONS COMMISSION
Laboratory Division
3433 Oakland Mills Road
Columbia, MD 21046

February 27, 2003

Registration Number: 98471

C & C Laboratory Co., Ltd.
No. 81-1, 210 Lane,
Feng-2nd Road, La-Cha-Hsiang
Taoyuan
Taiwan, R.O.C.
Attention: Kurt Chen

Re: Measurement facility located at Taoyuan
Site No. 1 & 2 (D & 10mm)
Date of Listing: February 27, 2003

Confirmation:

Your submission of the description of the subject measurement facility has been reviewed and found to be in compliance with the requirements of Section 2.944 of the FCC Rules. The description has, therefore, been placed on the web site of your organization added to the Commission's list of facilities whose measurement data will be accepted in conjunction with applications for Certification under Parts 17 or 18 of the Commission's Rules. Please note that this listing must be updated for any changes made to the facility, and at least every three years from the date of listing the data on file must be certified as current.

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Sincerely,

Thomas W. Phillips
Director/Engineer

COMMERCE
MINISTRY OF COMMERCE
To Ministry, Taichung, Taiwan

ENG 318
AJD

22 January 1999

C & C Laboratory Co Ltd
(P.F.)
No. 344
Fu Ching Street
Taichung
TAIWAN ROC

Attention: Mr Tony Huang

Dear Sir

LABORATORY APPROVAL

Thank you for your submission of 21 January regarding the approval of your testing laboratory to the Ministry of Commerce's laboratory approval criteria. Thank you for your interest in this matter.

I am pleased to advise that your submission has been successful and your laboratory has been added to the list of Ministry-approved laboratories. Your approved status is valid until 31 December 1999. At this time, the Approved Laboratory scheme will cease operation with the implementation of the new telecommunications regulations. Test reports from your laboratory will be accepted under the new framework. Please find enclosed a copy of the Ministry's discussion paper, DP10, outlining the proposed compliance process from 1 January 1999.

If you have any further questions on this matter please do not hesitate to contact me.

Yours faithfully


Andrew Dyke
Senior Technical Officer (Regulatory)

Operations and 20th Management Bureau, Ministry of Commerce, 22 Kwei-Sung Road, Taipei, Taiwan
Tel: 886-2-247-3449 ext. 184-470 (M/F) Fax: 886-2-247-3449

COMMERCE
MINISTRY OF COMMERCE
To Ministry, Taichung, Taiwan

ENG 318
AJD

22 January 1999

C & C Laboratory Co Ltd
(P.F.)
No. 344
Fu Ching Street
Taichung
TAIWAN ROC

Attention: Mr Tony Huang

Dear Sir

LABORATORY APPROVAL

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Yours faithfully


Andrew Dyke
Senior Technical Officer (Regulatory)

Operations and 20th Management Bureau, Ministry of Commerce, 22 Kwei-Sung Road, Taipei, Taiwan
Tel: 886-2-247-3449 ext. 184-470 (M/F) Fax: 886-2-247-3449



World-wide Testing and Certification

ELA 4BTTT

EMC Laboratory Authorisation

Aut. No.: ELA 192

Testing of

Radio & Telecommunications Terminal Equipment

EMC Laboratory: C & C Laboratory Co., Ltd.
No. 15, 14 Lin, Chiu Tse Chi, Lu Chu Hsiang,
Taoyuan 338, Taiwan R.O.C.

Scope of Authorisation: All CENELEC and ETSI standards (ENs and ETSs that are listed in the accompanying page, and all of the corresponding CISPR, IEC, and ISO EMC standards). This authorisation covers all of the EMC-related testing and documentation within the scope of the Radio and Telecommunications Terminal Equipment (RATTE) Directive (i.e. 1999/5/EC).

NOTE: This authorisation also covers EMC-related testing and documentation that is within the scope of Article 10.5 of the EMC Directive (i.e. 89/368/EEC as amended by 92/31/EEC).

This Authorisation Document confirms that the above-mentioned EMC Laboratory has been validated against EN 45001 and found to be compliant. The laboratory also fulfills the conditions described in Nemko Document ELA 10. During Nemko's visit to the laboratory, an assessment was made of the relevant parts of your organisation - i.e. facilities, personnel qualifications, test equipment, and testing practices. It was found that the EMC Laboratory is capable of performing tests within the Scope of Authorisation given in the accompanying page. Accordingly, Nemko will accept your test reports as a basis for issuing conformity to claim EMC standards for the products in question under the European Union's Directive (i.e. 1999/5/EC).

For Type Examination Certification(s) to be issued by Nemko, your EMC Laboratory's test reports will be accepted by Nemko if they are enclosed with the Application Form submitted by the manufacturer.

In order to maintain this Authorisation, the information given in the enclosed ELA-INFO (if any) must be carefully followed. Nemko is to be promptly notified about any changes and/or deviations at your EMC Laboratory which may affect the basis for this Authorisation. The Authorisation may at any time be withdrawn if the conditions are no longer considered to be fulfilled.

The Authorisation is valid through 31. December 2003.

Date 26 April 2001

Per Nemko AS:

Kjell Bergh

Kjell Bergh, Nemko Group EMC Co-ordinator

Product address:
Nemko AS
Nemko Group EMC Co-ordinator

Telephone:
+47 22 44 44 44
+47 22 44 44 44



World-wide Testing and Certification

ELA 4BTTT

EMC Laboratory Authorisation

Aut. No.: ELA 192

(Page 2 of 2)

SCOPE OF AUTHORISATION

Generic and product-family standards, R&TTE

EN 50145-118:2000 + A1:01	EN 50145-119:2000	EN 50145-120:2000
EN 50145-121:2000	EN 50145-122:2000	EN 50145-123:2000
EN 50145-124:2000	EN 50145-125:2000	EN 50145-126:2000
EN 50145-127:2000	EN 50145-128:2000	EN 50145-129:2000
EN 50145-130:2000	EN 50145-131:2000	EN 50145-132:2000
EN 50145-133:2000	EN 50145-134:2000	EN 50145-135:2000
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EN 50145-460:2000	EN 50145-461:2000	EN 50145-462:2000
EN 50145-463:		



World-wide Testing and Certification

ELA 4

**EMC Laboratory
MDD Authorisation**

Aut. No.: ELA 124b

EMC Laboratory: C & C Laboratory Co., Ltd.
No. 15, 14 Lin, Chin Twa Chh, Lu Chu Hsiang,
Taoyuan 338, Taiwan R.O.C.

Scope of Authorisation: EN 60601-1-2 and IEC 60601-1-2, the Collateral Standards for electromedical products, with particular application to EMC requirements only.

This Authorisation Document confirms that the above mentioned EMC Laboratory has been validated against EN 45001 and found to be compliant. The laboratory also fulfills the conditions described in Nemko Document ELA 10. During Nemko's visit to the laboratory an assessment was made of the relevant parts of your organisation - i.e. facilities, personnel qualifications, test equipment, and testing practices. It was found that the EMC Laboratory is capable of performing tests within the Scope of Authorisation listed above. Accordingly, Nemko will accept your test reports as a basis for attesting conformity to these EMC Standards for the products in question under either the European Union Medical Device Directive (MDD), 90/269/EEC, or the European Union Active Implantable Medical Device Directive (AIMD), 90/385/EEC, (as applicable).

In case of applications for Product Certification(s) to be issued by Nemko, your EMC Laboratory's test report(s) will be accepted by Nemko if they are enclosed with the Application Form submitted by the manufacturer.

In order to maintain the Authorisation, the information given in the enclosed ELA-REPORT (if any) must be carefully followed. Nemko is to be promptly notified about any changes in the situation at your EMC Laboratory which may affect the basis for this Authorisation. The Authorisation may at any time be withdrawn if the conditions are no longer considered to be fulfilled.

The Authorisation is valid through 31. December 2003.

Oso 17 December 2002

For Nemko AS:

Kjell Bergh
Kjell Bergh, Nemko Group EMC Co-ordinator

Postal address: C & C Laboratory Co., Ltd.
No. 15, 14 Lin, Chin Twa Chh, Lu Chu Hsiang,
Taoyuan 338, Taiwan R.O.C.

Telephone: +886 3 210 1000
Fax: +886 3 210 1000



World-wide Testing and Certification

ELA 4RTTE

EMC Laboratory Authorisation

Aut. No.: ELA 124c

**Testing of
Radio & Telecommunications Terminal Equipment**

EMC Laboratory: C & C Laboratory Co., Ltd.
No. 15, 14 Lin, Chin Twa Chh, Lu Chu Hsiang,
Taoyuan 338, Taiwan R.O.C.

Scope of Authorisation: All CENELEC and ETSI standards (RNs and ETSS) that are listed on the accompanying page, and all of the corresponding CISPR, IEC, and ISO EMC standards. This authorisation covers all of the EMC-related testing and documentation within the scope of the Radio and Telecommunications Terminal Equipment (R/TTE) Directive (i.e. 1999/5/EC).

NOTE: This authorisation also covers EMC-related testing and documentation that is within the scope of Article 10.5 of the EMC Directive (i.e. 89/368/EEC as amended by 93/32/EEC).

This Authorisation Document confirms that the above mentioned EMC Laboratory has been validated against EN 45001 and found to be compliant. The laboratory also fulfills the conditions described in Nemko Document ELA 10. During Nemko's visit to the laboratory, an assessment was made of the relevant parts of your organisation - i.e. facilities, personnel qualifications, test equipment, and testing practices. It was found that the EMC Laboratory is capable of performing tests within the Scope of Authorisation given on the accompanying page. Accordingly, Nemko will accept your test reports as a basis for attesting conformity to these EMC Standards for the products in question under the European Union's Directives specified above.

The Type Examination Certificate(s) to be issued by Nemko, your EMC Laboratory's test report(s) will be accepted by Nemko if they are enclosed with the Application Form submitted by the manufacturer.

In order to maintain the Authorisation, the information given in the enclosed ELA-REPORT (if any) must be carefully followed. Nemko is to be promptly notified about any changes in the situation at your EMC Laboratory which may affect the basis for this Authorisation. The Authorisation may at any time be withdrawn if the conditions are no longer considered to be fulfilled.

The Authorisation is valid through 31. December 2003.

Oso 17 December 2002

For Nemko AS:

Kjell Bergh
Kjell Bergh, Nemko Group EMC Co-ordinator

Postal address: C & C Laboratory Co., Ltd.
No. 15, 14 Lin, Chin Twa Chh, Lu Chu Hsiang,
Taoyuan 338, Taiwan R.O.C.

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World-wide Testing and Certification

ELA 4RTTE

EMC Laboratory Authorisation

Aut. No.: ELA 124c

(Page 2 of 2)

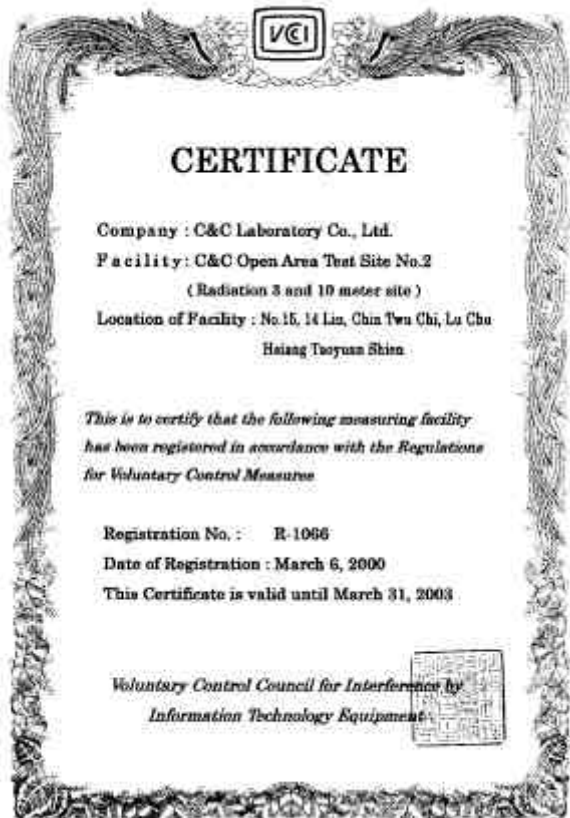
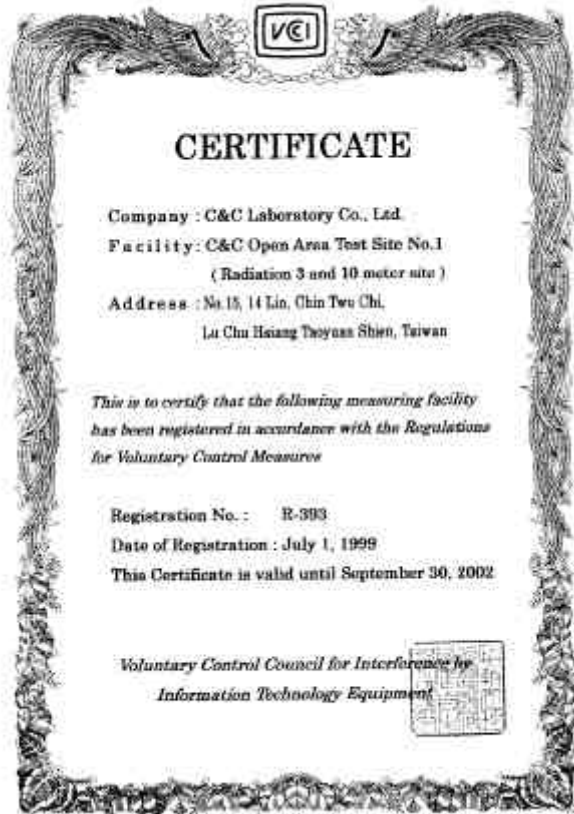
SCOPE OF AUTHORISATION

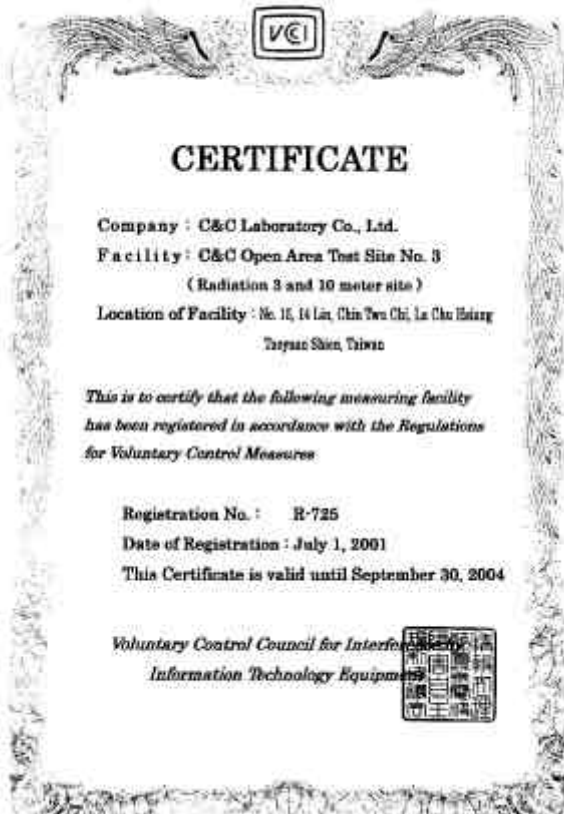
Generic and product-family standards, R&TTE

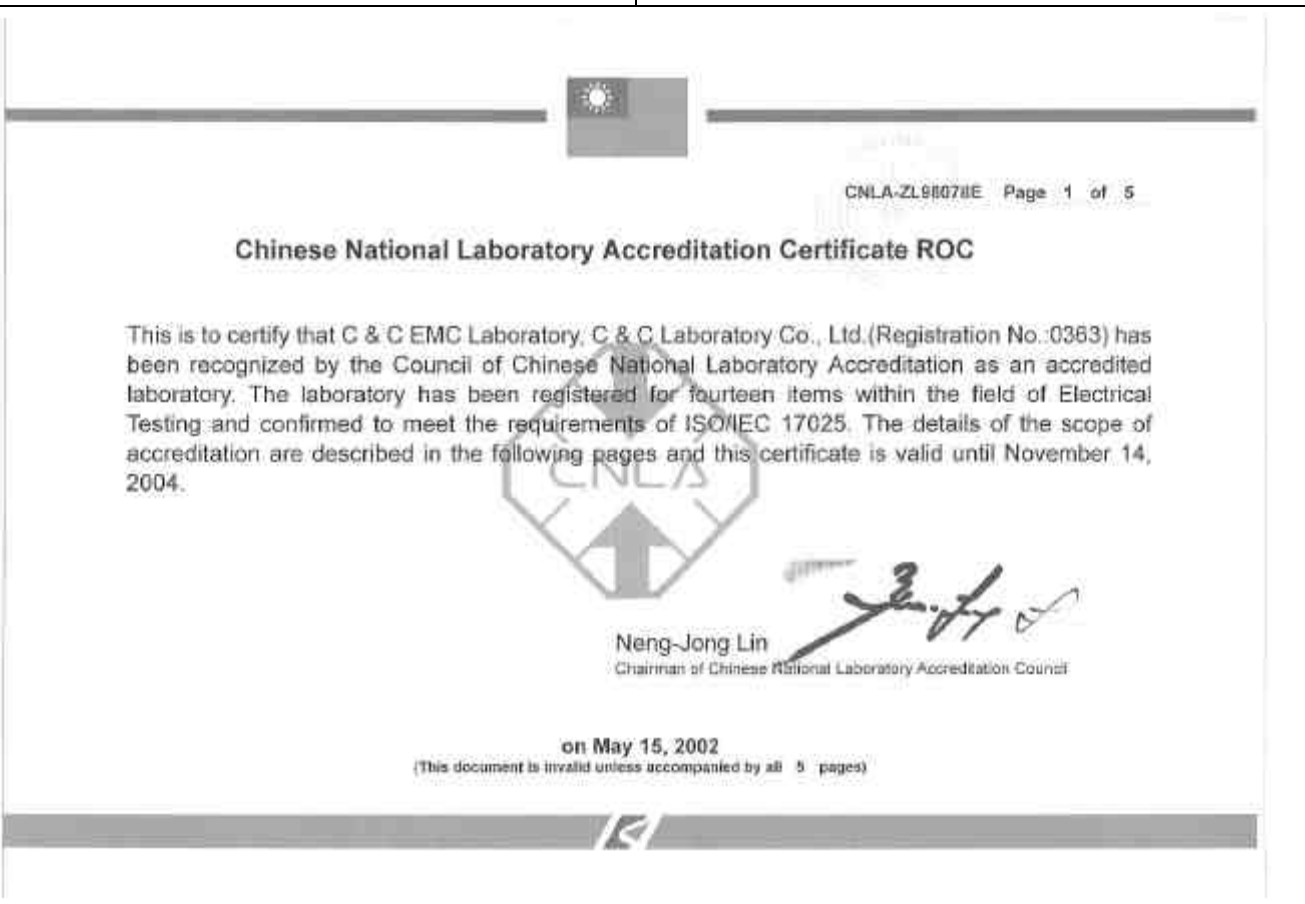
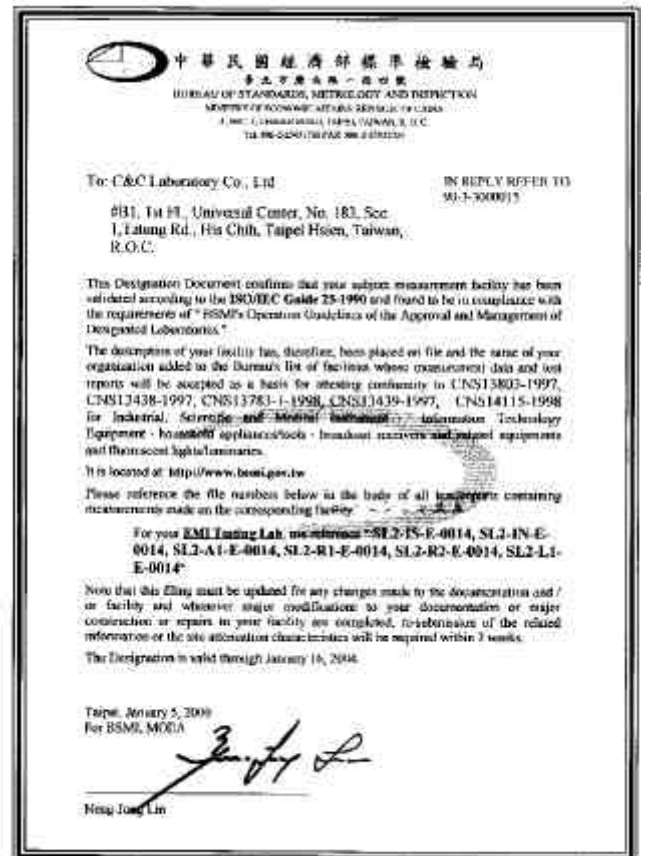
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EN 300 422-2 (1998)	ETS 300 443-1 (1998 + A1:01)	EN 300 443-1 (1998)
	EN 300 443-01 (1998)	
ETS 300 042 (1991)	ETS 300 043 (1991)	EN 300 043 (1991)
EN 300 043-01 (1991)	EN 300 043-01 (1991)	
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EN 300 443-01 (1998)		

Basic standards

EN 61010-1:1993 + A1:01 EN 61010-2:1993 + A1:01	EN 61010-4:1993 + A1:01 EN 61010-5:1993 + A1:01	EN 61010-6:1993 EN 61010-7:1993
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CNLA-ZL99078E Page 2 of 5

Organization	C & C Laboratory Co., Ltd.
Laboratory	C & C EMC Laboratory
Registration No.	0363
Laboratory Head	WANG, Charles
Testing Field	Electrical Testing
Date of Registration	1998.11.15
Date of Extension	2001.11.15

Registration items	Test Items	Test Methods	Ranges	Best Test capability recognized	Remarks
000289 Low power E.P. Equipment	Low power radiating equipment	ITU-T Rec. W.6-2 Annex A Technical Specification (2000.10) ETSI EN 300 328-1 V1.3.1 (2001-05) ETSI EN 300 328-2 V1.3.1 (2001-05) ETSI EN 300 328-3 V1.3.1 (2001-05) TDSI BS 300 328-2 V1.3.1 (2001-05) TDSI BS 300 328-3 V1.3.1 (2001-05) ETSI EN 300 328-3 V1.3.1 (2001-05)	0.4W-0.5W		
001102 Numbers: wireless numbers	TTE and peripheral products	IEC MO06-3-4(1995) A1(2001) EN 61000-3-2(1995) A1(1998), A2(1998), A14(2000)	RTN Voltage: 0-270VAC (Single Phase)50/60 Hz RMT current: 0-45 A Harmonic number: n=40 orders		
001103 Voltage Fluctuation rate and Flicker	TTE and peripheral Products	IEC 1000-3-3 (1994) EN 61000-3-3 (1995)	RTN Voltage: 0-230 VAC (Single Phase)50/60 Hz RMT Current: 0-16 A Standard impedance Ra = 0.4 Ω		



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Registration items	Test items	Test Methods	Ranges	Best Test capability recognized	Remarks
EMI13 Audio and television receivers and associated apparatus	Broadcast receivers and associated equipment	IEC 5013:1996A11:1996A11:1996 CISPR 15:1975A4:1983 CIS 1439:1999.1	IET Voltage:100-230 VAC (Single Phase)10/50 Hz EUT Current:0-30 A 0 kHz-1.75 MHz Conduction Emission: 0.1Hz-20 MHz Antenna Terminal: 30V/0.5-1.75 MHz Distal 100 frequencies: 30 MHz-1000MHz Disturbance Power: 30-200 MHz		
EMI14 Electrical appliances and systems	Household appliances (kitchen hoods and similar) appliances	IEC 55014-1:1996A41:1996A21:1999 CISPR 14-1:1996A41:1996A51:1998 CIS 1333A-1:1998.50	IET Voltage:0-230 VAC (Single-Phase)10/50/60 Hz EUT Current:0-300 A Conduction Emission: 0.1Hz-30 MHz Disturbance Power: 50-300 MHz		
EMI15 Fluorescent lamps and ballast (type)	Fluorescent lamps and luminaires	CISPR 15-1:1992 EN 55015-1:1995 CIS 14125:1998.1	IET Voltage:0-230 VAC (Single-Phase) Conduction emission frequency range:0 kHz-30 MHz Magnetic interference frequency range:0 MHz-30 MHz Magnetic loop current (inter-lamp line frequency range:130-5000 Hz Line 60 interference frequency		

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Registration items	Test items	Test Methods	Ranges	Best Test capability recognized	Remarks
E10122 System and components of the telecommunication and information technology	ITE and peripheral products	CISPR 22 (1997) EN 55022 (1998) CISPR 13 (1997) EN 55013 (1998) EN 55024 (1998) EN 55025 (1998) EN 55026 (1998)	range: 30 MHz-30.0 GHz EMI Voltage: 0-270 VAC (Single Phase) 50/60 Hz EMI Current: 0-200 A Conduction Interference: 150 kHz-50 MHz Radiation interference: 30 MHz-30.0 GHz		
E10209 Electrostatic discharge tests	ITE and peripheral products	IEC 61000-4-2 (1991) EN 61000-4-2 (1995) EN 15022-1 (1992)	EMI Voltage: 100-270 VAC (Single Phase) 50/60 Hz EMI Current: 0-200 A Air discharge: 0.1-25 kVAC Contact discharge: 0.1-25 kVAC		
E10211 Radiated susceptibility (V tests)	ITE and peripheral products	IEC 60060-3 (1994) IEC 1000-4-3 (1995) EN 61000-4-3 (1996) EN 50214 (1993)	EMI Voltage: 0-270 VAC (Single Phase) 50/60 Hz EMI Current: 0-200 A Frequency range: 100kHz-1.0 GHz (Field intensity: 10 V/m, 100 V/m, 1000 V/m)		
E10214 Electrical fast transient/burst tests	ITE and peripheral products	IEC 60060-4 (1995) IEC 1000-4-4 (1995) EN 61000-4-4 (1996) EN 15022-2 (1992)	EMI Voltage: 0-270 VAC (Single Phase) 50/60 Hz EMI Current: 0-200 A Equipment range: 0.2-4.5 kV		

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Registration items	Test items	Test Methods	Ranges	Best Test capability recognized	Remarks
E10215 Surge/immunity tests	ITE and peripheral products	IEC 1000-4-5 (1995) EN 50142 (1994) EN 15022-3 (1992) EN 61000-4-5 (1995)	EMI Voltage: 0-270 VAC (Single Phase) 50/60 Hz DC (0V) EMI Current: 0-200 A (AC/DC) Equipment range: 0.2-4.5 kV Test Ports: Power line, Signal line		
E10216 Conducted susceptibility tests	ITE and peripheral products	IEC 1000-4-6 (1995) EN 61000-4-6 (1996) EN 15041 (1992)	EMI Voltage: 0-270 VAC (Single Phase) 50/60 Hz EMI Current: 0-200 A Frequency range: 150 kHz-100 MHz (Modulation: 10%, 100% Modulation)		
E10218 Power frequency magnetic field immunity test	ITE and peripheral products	IEC 1000-4-8 (1995) EN 61000-4-8 (1995)	EMI Voltage: 0-270 VAC (Single Phase) 50/60 Hz EMI Current: 0-200 A Continuous magnetic field: 1-100 A/m		
E10219 Voltage dip, short interruption and voltage variation immunity tests	ITE and peripheral products	IEC 1000-4-11 (1996) EN 61000-4-11 (1996)	EMI Voltage: 100-270 VAC (Single Phase) 50/60 Hz EMI Current: 0-200 A Voltage variation: 100 % Voltage dip: 0-100 % Voltage variation: Standard variation wave shape		

7 TEST EQUIPMENT LIST (EMISSION)

Instrumentation: The following list contains equipment used at C & C Laboratory, Co., Ltd. for testing. The equipment conforms to the CISPR 16-1 / ANSI C63.2-1988 Specifications for Electromagnetic Interference and Field Strength Instrumentation from 9kHz to 1.0 / 2.0 GHz.

Equipment used during the tests:

Open Area Test Site: # 1

Open Area Test Site # 1					
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE
Q.P Adaptor	HP	85650A	2043A00373	06/12/2002	06/11/2003
RF Pre-selector	HP	85685A	3010A01113	06/12/2002	06/11/2003
Spectrum Analyzer	HP	8568B	2415A00314	06/12/2002	06/11/2003
S.P.A Display	HP	85662A	2403A06937	06/12/2002	06/11/2003
Spectrum Analyzer	Anritsu	MS2601A	MT09950	N/A	N/A
Pre-Amplifier	HP	8447D	2944A08432	N/A	N/A
Bilog Antenna	CHASE	CBL6112A	2309	02/09/2002	02/08/2003
Turn Table	EMCO	2081-1.21	N/A	N.C.R	N.C.R
Antenna Tower	EMCO	2075-2	9707-2604	N.C.R	N.C.R
Controller	EMCO	2090	N/A	N.C.R	N.C.R
RF Switch	ANRITSU	MP59B	M54367	N.C.R	N.C.R
Site NSA	C&C	N/A	N/A	08/31/2002	08/30/2003

Conducted Emission Test Site: # 3

Conducted Emission Test Site # 3					
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE
EMI Test Receiver	R&S	ESHS30	828144/003	08/08/2002	08/07/2003
LISN	R&S	ESH2-Z5	843285/010	12/16/2002	12/15/2003
LISN	EMCO	3825/2	9003-1628	07/26/2002	07/25/2003

The calibrations of the measuring instruments, including any accessories that may effect such calibration, are checked frequently to assure their accuracy. Adjustments are made and correction factors applied in accordance with instructions contained in the manual for the measuring instrument.

8 TEST EQUIPMENT LIST (IMMUNITY)

Power Harmonic & Voltage Fluctuation/Flicker Measurement (61000-3-2&-3-3)					
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL DUE.
Harmonic & Flicker Tester	HAEFELY TRENCH	PHF555	080 419-25	10/14/2002	10/13/2003
ESD test (61000-4-2)					
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL DUE.
ESD Generator	NoiseKen	ESS-2001	ESS0210582	06/18/2002	06/17/2003
Radiated Electromagnetic Field immunity Measurement (61000-4-3)					
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL DUE.
S.G.	R&S	SMY02	100094	08/08/2002	08/07/2003
Power Amplifier	ar	150W1000	300300	N/A	N/A
Power Antenna	EMCO	93141	9712-1083	N/A	N/A
EM PROBE	GW	EMR-30	L-0013	05/23/2002	05/22/2003
Fast Transients/Burst test (61000-4-4)					
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL DUE.
Fast Transients/Burst Generator	HAEFELY TRENCH	PEFT-JUNIOR	583 333-117	08/22/2002	08/21/2003
Clamp	HAEFELY TRENCH	093 506.1	080 421.13	N/A	N/A
Surge Immunity test (61000-4-5)					
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL DUE.
Surge Tester	HAEFELY TRENCH	PSUGER 4010	583 334-71	09/03/2002	09/02/2003
CS test (61000-4-6)					
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL DUE.
S.G.	R&S	SMY02	100094	08/08/2002	08/07/2003
Power Amplifier	ar	500A100A	300299	N/A	N/A
CDN	Lüthi	801-M3	1879	03/05/2002	03/04/2003
CDN	MEB	M2	A3002010	04/24/2002	04/23/2003
CDN	SCHAFFNER	T400	16906	10/17/2002	10/16/2003
Power Frequency Magnetic Field Immunity test (61000-4-8)					
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL DUE.
TRIAX ELF Magnetic Field Meter	F.W.BELL	4090	9711	10/21/2002	10/20/2003
Clamp Meter	National	300K	11-5980 K	11/19/2002	11/18/2003
Magnetic Field Tester	HAEFELY TRENCH	MAG 100.1	080 938-01	N/A	N/A
Voltage Dips/Short Interruption and Voltage Variation Immunity test (61000-4-11)					
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL DUE.
Dips/Interruption and Variations Simulator	HAEFELY TRENCH	PLINE 1610	080 344-05	04/08/2002	04/07/2003

9 SECTION 1 EN 55022 (LINE CONDUCTED & RADIATED EMISSION)

9.1 MEASUREMENT PROCEDURE (PRELIMINARY LINE CONDUCTED EMISSION TEST)

- 1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per EN 55022 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- 2) Support equipment, if needed, was placed as per EN 55022.
- 3) All I/O cables were positioned to simulate typical actual usage as per EN 55022.
- 4) The EUT received AC power through a Line Impedance Stabilization Network (LISN) which supplied power source and was grounded to the ground plane.
- 5) All support equipments received power from a second LISN supplying power of 110VAC/60Hz, if any.
- 6) The EUT test program was started. Emissions were measured on each current carrying line of the EUT using a spectrum analyzer / Receiver connected to the LISN powering the EUT. The LISN has two monitoring points: Line 1 (Hot Side) and Line 2 (Neutral Side). Two scans were taken: one with Line 1 connected to Analyzer / Receiver and Line 2 connected to a 50 ohm load; the second scan had Line 1 connected to a 50 ohm load and Line 2 connected to the Analyzer / Receiver.
- 7) Analyzer / Receiver scanned from 150kHz to 30MHz for emissions in each of the test modes.
- 8) During the above scans, the emissions were maximized by cable manipulation.
- 9) The following test mode(s) were scanned during the preliminary test:

Mode(s): (Customer defined)

1. **640 × 480 Resolution / 100Mbps (MBPC-400-9577)**
 2. **800 × 600 Resolution/ 100Mbps (MBPC-400-9577)**
 3. **1024 × 768 Resolution/ 100Mbps (MBPC-400-9577)**
 4. **1024 × 768 Resolution/ 10Mbps (MBPC-400-9577)**
 5. **1024 × 768 Resolution/ 100Mbps (MBPC-400-9575)**
- 10) After the preliminary scan, we found the following test mode producing the highest emission level.

Mode: 3.

Then, the EUT configuration and cable configuration of the above highest emission level were recorded for reference of final testing.

MEASUREMENT PROCEDURE (FINAL LINE CONDUCTED EMISSION TEST)

- 1) EUT and support equipment was set up on the test bench as per step 10 of the preliminary test.
- 2) A scan was taken on both power lines, Line 1 and Line 2, recording at least the six highest emissions. Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. If EUT emission level was less –2dB to the A.V. limit in Q.P. mode, then the emission signal was re-checked using an A.V. detector.
- 3) The test data of the worst case condition(s) was reported on the Summary Data page.

Data Sample:

Freq. MHz	Q.P. Raw dBuV	Average Raw dBuV	Q.P. Limit dBuV	Average Limit dBuV	Q.P. Margin dB	Average Margin dB	Note
x.xx	43.95	---	56	46	-12.05	---	L1

Freq.	= Emission frequency in MHz
Raw dBuV	= Uncorrected Analyzer/Receiver reading + Insertion loss of LISN, if it > 0.5 dB
Limit dBuV	= Limit stated in standard
Margin dB	= Reading in reference to limit
Note	= Current carrying line of reading
“---“	= The emission level complied with the Average limits, with at least 2dB margin limits, so no further recheck.

Calculation example:

$$\text{Margin (dB)} = \text{RAW (dBuV)} - \text{Limit (dBuV)}$$

LINE CONDUCTED EMISSION LIMIT (EN 55022)

Frequency	Maximum RF Line Voltage	
	Q.P.	AVERAGE
150kHz-500kHz	79dBuV	66dBuV
500kHz-5MHz	73dBuV	60dBuV
5MHz-30MHz	73dBuV	60dBuV

Note: The lower limit shall apply at the transition frequency.

9.2 MEASUREMENT PROCEDURE (COMMON MODE CONDUCTED EMISSION MEASUREMENT)

1. Selecting ISN for unscreened cable or a current probe for screened cable to take measurement.
2. The port of the EUT was connected to the remote side support equipment through the ISN/Current Probe and communication in normal condition.
3. Making a overall range scan by using the test receiver controlled by controller and record at least six highest emissions for showing in the test report.
4. Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit.
5. In case of measuring on the screened cable, the current limit shall be applied, otherwise the voltage limit should be applied.
6. The test data of the worst case condition(s) was reported on the Summary Data page.

Data Sample:

Freq. MHz	Q.P. Raw dBuV	Average Raw dBuV	Q.P. Limit dBuV	Average Limit dBuV	Q.P. Margin dB	Average Margin dB	Note
x.xx	43.95	---	74	64	-30.05	---	

Freq.

Raw dBuV

Limit dBuV

Margin dB

Note

“---“

= Emission frequency in MHz

= Uncorrected Analyzer / Receiver reading

= Limit stated in standard

= Reading in reference to limit

= Current carrying line of reading

= The emission level complied with the Average limits, with at least 2 dB margin, so no further recheck.

COMMON MODE CONDUCTED EMISSION LIMIT AT TELECOMMUNICATION PORTS

<input checked="" type="checkbox"/> CE-Mark (EN 55022:1998)					
CLASS	Measuring Band	Voltage limit dB(uV)		Current limit dB(uA)	
		Q.P.	AV	Q.P.	AV
A	150kHz-500kHz	97-87	84-74	53-43	40-30
	500kHz-30MHz	87	74	43	30

Note: The lower limit shall apply at the transition frequency.

9.3 MEASUREMENT PROCEDURE (PRELIMINARY RADIATED EMISSION TEST)

- 1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden turntable with a height of 0.8 meters is used which is placed on the ground plane as per EN 55022 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- 2) Support equipment, if needed, was placed as per EN 55022.
- 3) All I/O cables were positioned to simulate typical actual usage as per EN 55022.
- 4) The EUT received AC power source from the outlet socket under the turntable. All support equipment received 110VAC/60Hz power from another socket under the turntable, if any.
- 5) The antenna was placed at 10 meter away from the EUT as stated in EN 55022. The antenna connected to the Analyzer via a cable and at times a pre-amplifier would be used.
- 6) The Analyzer / Receiver quickly scanned from 30MHz to 1000MHz. The EUT test program was started. Emissions were scanned and measured rotating the EUT to 360 degrees and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- 7) The following test mode(s) were scanned during the preliminary test:

Mode(s): (Customer Defined)

1. **640 × 480 Resolution / 100Mbps (MBPC-400-9577)**
 2. **800 × 600 Resolution/ 100Mbps (MBPC-400-9577)**
 3. **1024 × 768 Resolution/ 100Mbps (MBPC-400-9577)**
 4. **1024 × 768 Resolution/ 10Mbps (MBPC-400-9577)**
 5. **1024 × 768 Resolution/ 100Mbps (MBPC-400-9575)**
- 8) After the preliminary scan, we found the following test mode producing the highest emission level.

Mode: 3.

Then, the EUT and cable configuration, antenna position, polarization and turntable position of the above highest emission level were recorded for final testing.

MEASUREMENT PROCEDURE (FINAL RADIATED EMISSION TEST)

- 1) EUT and support equipment were set up on the turntable as per step 8 of the preliminary test.
- 2) The Analyzer / Receiver scanned from 30MHz to 1000MHz. Emissions were scanned and measured rotating the EUT to 360 degrees, varying cable placement and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- 3) Recorded at least the six highest emissions. Emission frequency, amplitude, antenna position, polarization and turntable position were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit and only Q.P. reading is presented.
- 4) The test data of the worst case condition(s) was reported on the Summary Data page.

Data Sample:

Freq. (MHz)	Raw Data (dBuV/m)	Corr. Factor (dB)	Emiss. Level (dBuV/m)	Limits	Margin (dB)
xx.xx	14.0	11.2	26.2	30	-3.8

Freq.	= Emission frequency in MHz
Raw Data (dBuV/m)	= Uncorrected Analyzer / Receiver reading
Corr. Factor (dB)	= Antenna factor + Cable loss – Amplifier gain
Emiss. Level (dBuV/m)	= Raw reading converted to dBuV/m and CF added
Limit (dBuV/m)	= Limit stated in standard
Margin (dB)	= Reading in reference to limit
P	= Peak Reading
Q	= Quasi-peak Reading
A	= Average Reading

Calculation example:

$$\text{Margin (dB)} = \text{Emiss. Level (dBuV/m)} - \text{Limits (dBuV/m)}$$

$$\text{Emission Level (dBuV/m)} = \text{Raw Data (dBuV/m)} + \text{Corr Factor (dB)}$$

RADIATED EMISSION LIMIT

Frequency (MHz)	Distance (m)	Maximum Field Strength Limit (dBu V/m/ Q.P.)
30-230	10	30
230-1000	10	37

Note: The lower limit shall apply at the transition frequency.

10 BLOCK DIAGRAM OF TEST SETUP

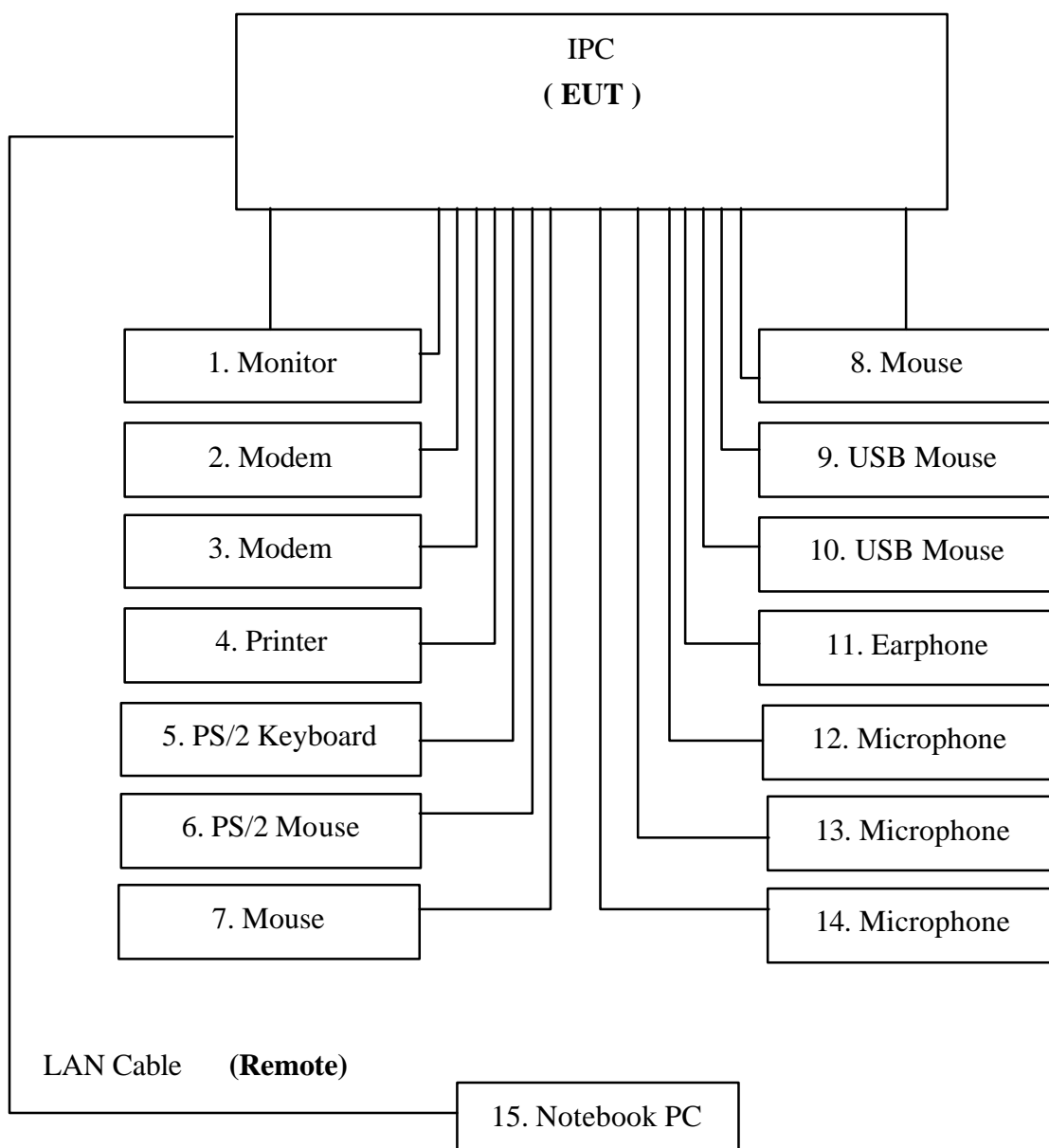
System Diagram of Connections between EUT and Simulators

EUT: IPC

Trade Name: Advantech

Model Number: MBPC-400-9577

Power Cord: Unshielded, 1.8m



11 SUMMARY DATA

(LINE CONDUCTED TEST)

Model Number: MBPC-400-9577

Location: Site # 3

Tested by: Tommy Lin

Test Mode: Mode 3

Test Results: Passed

Temperature: 23°C

Humidity: 64%RH

(The chart below shows the highest readings taken from the final data)

FREQ MHz	Q.P. RAW dBuV	AVG RAW dBuV	Q.P. Limit dBuV	AVG Limit dBuV	Q.P. Margin dB	AVG Margin dB	NOTE
0.150	51.30	---	79.00	66.00	-27.70	---	L1
18.324	38.30	---	73.00	60.00	-34.70	---	L1
19.467	41.40	---	73.00	60.00	-31.60	---	L1
21.376	38.00	---	73.00	60.00	-35.00	---	L1
22.403	38.10	---	73.00	60.00	-34.90	---	L1
28.714	37.40	---	73.00	60.00	-35.60	---	L1
0.150	49.30	---	79.00	66.00	-29.70	---	L2
15.864	34.10	---	73.00	60.00	-38.90	---	L2
17.293	33.90	---	73.00	60.00	-39.10	---	L2
17.904	34.00	---	73.00	60.00	-39.00	---	L2
19.476	41.30	---	73.00	60.00	-31.70	---	L2
20.961	33.70	---	73.00	60.00	-39.30	---	L2

L1 = Line One (Hot side) / L2 = Line Two (Neutral side)

****NOTE:** “---” denotes the emission level was or more than 2dB below the Average limit,
so no re-check anymore.

SUMMARY DATA

(COMMON MODE CONDUCTED EMISSION MEASUREMENT)

(LAN Port)

Model Number: MBPC-400-9577

Location: Site # 3

Tested by: Tommy Lin

Test Mode: Mode 3

Test Results: Passed

Temperature: 23°C

Humidity: 64%RH

(The chart below shows the highest readings taken from the final data)

FREQ MHz	Q.P. RAW dBuV	AVG RAW dBuV	Q.P. Limit dBuV	AVG Limit dBuV	Q.P. Margin dB	AVG Margin dB	NOTE
0.150	64.70	---	97.00	84.00	-32.30	---	10Base
5.051	54.60	---	87.00	74.00	-32.40	---	10Base
10.000	79.20	60.10	87.00	74.00	-7.80	-13.90	10Base
10.150	51.40	---	87.00	74.00	-35.60	---	10Base
11.963	54.10	---	87.00	74.00	-32.90	---	10Base
20.000	74.30	---	87.00	74.00	-12.70	---	10Base
21.664	61.70	---	87.00	74.00	-25.30	---	100Base
23.133	64.90	---	87.00	74.00	-22.10	---	100Base
24.353	63.40	---	87.00	74.00	-23.60	---	100Base
26.614	64.00	---	87.00	74.00	-23.00	---	100Base
27.167	62.10	---	87.00	74.00	-24.90	---	100Base
29.113	61.70	---	87.00	74.00	-25.30	---	100Base

NOTE: “---” denotes the emission level was or more than 2dB below the Average limit, so no re-check anymore.

SUMMARY DATA

(RADIATED EMISSION TEST)

Model Number: MBPC-400-9577

Location: Site # 1

Tested by: Sam Chang

Polar: Vertical--10m

Test Mode: Mode 3

Test Results: Passed

Detector Function: Quasi-Peak

Temperature: 25°C

Humidity: 50%RH

(The chart below shows the highest readings taken from the final data)

Freq. (MHz)	Raw Data (dBuV/m)	Corr. Factor (dB)	Emiss. Level (dBuV/m)	Limits	Margin (dB)
37.02	18.3	16.8	35.1	40.0	-4.9
64.64	22.2	5.7	27.9	40.0	-12.1
133.00	18.9	12.1	31.0	40.0	-9.0
140.00	19.4	12.3	31.7	40.0	-8.3
336.06	19.5	17.1	36.6	47.0	-10.4
422.24	19.8	19.6	39.4	47.0	-7.6

SUMMARY DATA

(RADIATED EMISSION TEST)

Model Number: MBPC-400-9577

Location: Site # 1

Tested by: Sam Chang

Polar: Horizontal--10m

Test Mode: Mode 3

Test Results: Passed

Detector Function: Quasi-Peak

Temperature: 25°C

Humidity: 50%RH

(The chart below shows the highest readings taken from the final data)

Freq. (MHz)	Raw Data (dBuV/m)	Corr. Factor (dB)	Emiss. Level (dBuV/m)	Limits	Margin (dB)
80.84	24.0	7.2	31.2	40.0	-8.8
140.00	18.0	12.3	30.3	40.0	-9.7
240.00	22.5	12.2	34.7	47.0	-12.3
299.40	20.4	15.6	36.0	47.0	-11.0
336.03	25.5	17.1	42.6	47.0	-4.4
486.40	13.7	20.5	34.2	47.0	-12.8

12 SECTION 2 EN 61000-3-2 & EN 61000-3-3 (POWER HARMONICS & VOLTAGE FLUCTUATION / FLICKER)

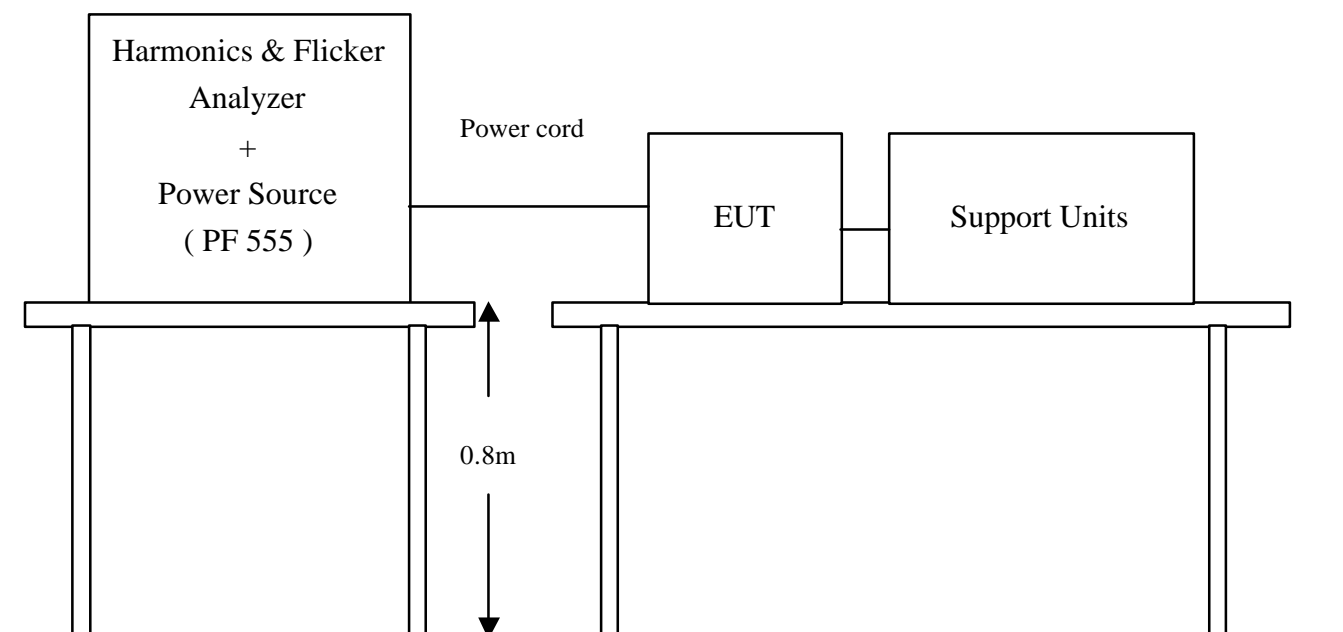
POWER HARMONICS MEASUREMENT

Port : AC mains
Basic Standard : EN 61000-3-2 (1995 + A1: 1998 + A2: 1998 + A14: 2000)
Limits : ☐ CLASS A ; ☒ CLASS D
Tester : Tommy Lin
Temperature : 22°C
Humidity : 50%

VOLTAGE FLUCTUATION/FLICKER MEASUREMENT

Port : AC mains
Basic Standard : EN 61000-3-3 (1995)
Limits : § 5 of EN 61000-3-3
Tester : Tommy Lin
Temperature : 22°C
Humidity : 50%

Block Diagram of Test Setup:



Result:

Please see the attached test data.

EN 61000-3-2 TEST REPORT 2003/1/22 06:45 PM

Unit: IPC

Model No.: MBPC-400-9577

Remarks: TEMP:22°C HUM:50%

Operator: Tommy Lin

=====

TEST SETUP

Test Freq.:	50.00 Hz.	Test Voltage:	230.0 vac
Waveform :	SINE	Test Time:	2.5 min.
Classification :	CLASS D	Test Type:	STEADY-STATE
Prog. Zo Enabled:	YES	Prog. Zo:	0.000
Motor Driven with Phase Angle Control:	NO		
Impedance selected:	DIRECT		
Synthetic R+L Enabled:	NO		
Resistance:	0.380 Ohms	Inductance:	460.000 uH

MAX WATTS:42.5W

TEST DATA

Result: PASS

Harmonic Current Results

Hn	AMPS	LO Limit	HI Limit	Result
0	0.000	0.000	0.000	PASS
1	0.181	NaN	NaN	PASS
2	0.001	1.080	1.080	PASS
3	0.161	2.300	2.300	PASS
4	0.001	0.430	0.430	PASS
5	0.147	1.140	1.140	PASS
6	0.001	0.300	0.300	PASS
7	0.127	0.770	0.770	PASS
8	0.001	0.230	0.230	PASS
9	0.105	0.400	0.400	PASS
10	0.001	0.184	0.184	PASS
11	0.083	0.330	0.330	PASS
12	0.000	0.153	0.153	PASS
13	0.061	0.210	0.210	PASS
14	0.000	0.131	0.131	PASS
15	0.042	0.150	0.150	PASS
16	0.000	0.115	0.115	PASS
17	0.028	0.132	0.132	PASS
18	0.000	0.102	0.102	PASS
19	0.017	0.118	0.118	PASS
20	0.000	0.092	0.092	PASS



21	0.011	0.107	0.107	PASS
22	0.000	0.084	0.084	PASS
23	0.007	0.098	0.098	PASS
24	0.000	0.077	0.077	PASS
25	0.004	0.090	0.090	PASS
26	0.000	0.071	0.071	PASS
27	0.002	0.083	0.083	PASS
28	0.000	0.066	0.066	PASS
29	0.002	0.078	0.078	PASS
30	0.000	0.061	0.061	PASS
31	0.003	0.073	0.073	PASS
32	0.000	0.058	0.058	PASS
33	0.004	0.068	0.068	PASS
34	0.000	0.054	0.054	PASS
35	0.004	0.064	0.064	PASS
36	0.000	0.051	0.051	PASS
37	0.003	0.061	0.061	PASS
38	0.000	0.048	0.048	PASS
39	0.002	0.058	0.058	PASS
40	0.000	0.046	0.046	PASS

END OF REPORT

EN 61000-3-3 TEST REPORT 2003/1/22 03:48 PM

Unit: IPC

Model No.: MBPC-400-9577 (Continue)

Remarks: TEMP:22°C HUM:50%

Operator: Tommy Lin

=====

TEST SETUP

Test Freq.:	50.00 Hz.	Test Voltage:	230.0 vac
Waveform :	SINE		
Test Time:	10.0 min.	Tshort:	10.0 min.
Prog. Zo Enabled:	YES	Prog. Zo:	0.000
Voltage Change less than once per Hour:		NO	
Impedance selected:		DIRECT	
Synthetic R+L Enabled:		NO	
Resistance:	0.380 Ohms	Inductance:	460.000 uH

TEST DATA

Result: PASS

	EUT Data	Limit	Result	Test Enabled
Pst max	0.001	1.00	PASS	true
Plt max	0.001	0.65	PASS	true
dc %	0.00	3.00	PASS	true
dmax %	0.00	4.00	PASS	true
d(t) sec.	0.00	0.20	PASS	true

Power Source Data

Source Pst max	0.021	0.400	PASS	true
% THD	0.03	3.00	PASS	true

END OF REPORT

EN 61000-3-3 TEST REPORT 2003/1/23 09:59 AM

Unit: IPC

Model No.: MBPC-400-9577 (Manual Switch)

Remarks: TEMP:22°C HUM:50%

Operator: Tommy Lin

=====

TEST SETUP

Test Freq.:	50.00 Hz.	Test Voltage:	230.0 vac
Waveform :	SINE		
Test Time:	10.0 min.	Tshort:	10.0 min.
Prog. Zo Enabled:	YES	Prog. Zo:	0.000
Voltage Change less than once per Hour:		NO	
Impedance selected:		DIRECT	
Synthetic R+L Enabled:		NO	
Resistance:	0.380 Ohms	Inductance:	460.000 uH

TEST DATA

Result: PASS

	EUT Data	Limit	Result	Test Enabled
Pst max	0.091	1.00	PASS	true
Plt max	0.091	0.65	PASS	true
dc %	0.00	3.00	PASS	true
dmax %	0.00	4.00	PASS	true
d(t) sec.	0.00	0.20	PASS	true

Power Source Data

Source Pst max	0.021	0.400	PASS	true
% THD	0.03	3.00	PASS	true

END OF REPORT

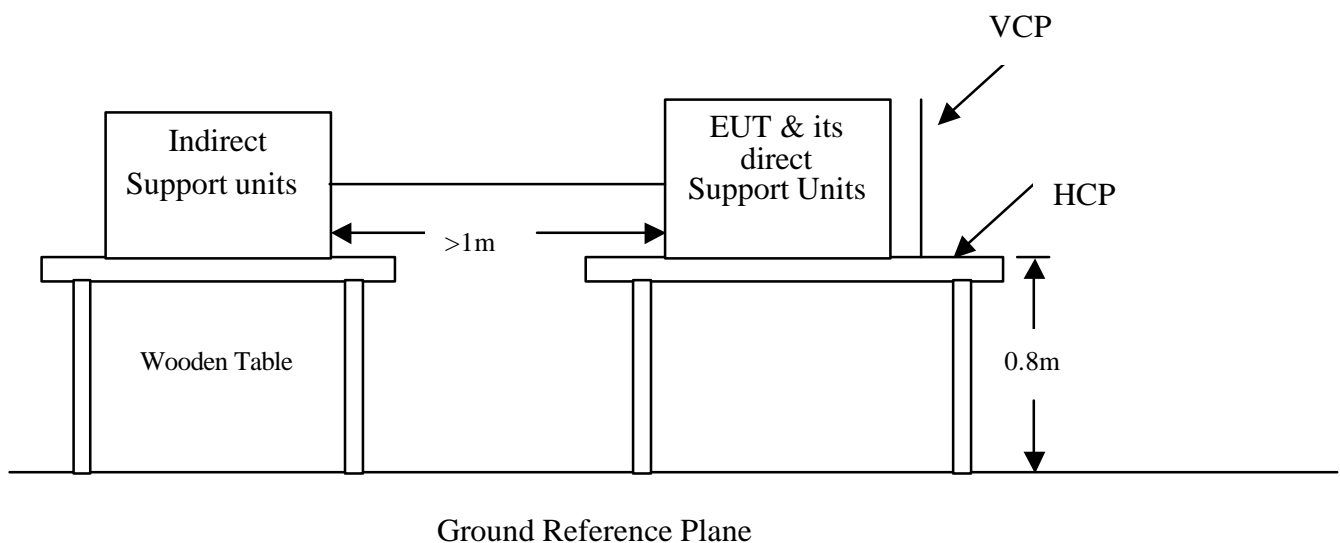
13 SECTION 3 IEC 61000-4-2 (ELECTROSTATIC DISCHARGE)

ELECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST

Port : Enclosure
Basic Standard : IEC 61000-4-2
Test Level : ± 8 kV (Air Discharge)
 ± 4 kV (Contact Discharge)
 ± 4 kV (Indirect Discharge)
Performance Criteria : B (Standard require)
Tester : Tommy Lin
Temperature : 22°C
Humidity : 50%
Pressure : 1008mbar

Block Diagram of Test Setup:

(The 470 k ohm resistors are installed per standard requirement)



Test Procedure:

1. The EUT was located 0.1 m minimum from all side of the HCP.
2. The indirect support units were located 1m minimum away from the EUT, but direct support unit was/ were located at same location as EUT on the HCP and keep at a distance of 10 cm with EUT.
3. A scroll 'H' test program was loaded and executed in Windows mode.
4. The EUT sent above message to EUT Panel and monitor and related peripherals through the test.
5. Active the communication function if the EUT with such port(s).
6. As per the requirement of EN 55024; applying direct contact discharge at the sides other than front of EUT at minimum 50 discharges (25 positive and 25 negative) if applicable, can't be applied direct contact discharge side of EUT then the indirect discharge shall be applied. One of the test points shall be subjected to at least 50 indirect discharge (contact) to the front edge of horizontal coupling plane.
7. Other parts of EUT where it is not possible to perform contact discharge then selecting appropriate points of EUT for air discharge, a minimum of 10 single air discharges shall be applied.
8. The application of ESD to the contact of open connectors is not required.
9. The EUT direct connection units also need to be applied ESD at the port of EUT cable connected
10. Putting a mark on EUT to show tested points. The following test condition was followed during the tests.

Note: As per IEC 61000-4-2:2001, with two 470k bleed resistors cable is connected between the EUT and HCP during the test applicable for power ungrounded or battery operating unit only.

The electrostatic discharges were applied as follows:

Amount of Discharges	Voltage	Coupling	Result (Pass/Fail)
Mini 10 /Point	± 8 kV	Air Discharge	Pass
Mini 25 /Point	± 4 kV	Contact Discharge	Pass
Mini 25 /Point	± 4 kV	Indirect Discharge HCP (Front)	Pass
Mini 25 /Point	± 4 kV	Indirect Discharge VCP (Right)	N/A
Mini 25 /Point	± 4 kV	Indirect Discharge VCP (Left)	N/A
Mini 25 /Point	± 4 kV	Indirect Discharge VCP (Back)	N/A

****The tested points to EUT, please refer to attached page.**

(Blue arrow mark for Contact Discharge and red arrow mark for Air Discharge)

Performance & Result:

- ☒ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

<input checked="" type="checkbox"/> PASS <input type="checkbox"/> FAILED
Observation: No any function degraded during the tests.

The Tested Points of EUT

(Photo 1 of 4)



(Photo 2 of 4)



The image shows the rear panel of a gold-colored industrial computer chassis. The panel is densely packed with various ports and connectors. On the left side, there are two blue 15-pin D-sub connectors (likely for video or serial), two blue 9-pin D-sub connectors (likely for serial), and a green 15-pin D-sub connector (likely for video). In the center, there is a blue 25-pin D-sub connector (likely for parallel or serial), a green 15-pin D-sub connector (likely for video), and a black 15-pin D-sub connector (likely for video). On the right side, there are two USB ports, a FireWire port, and a network port. Below these, there are several circular ports, including a power jack, a power switch, and several status LEDs. The chassis has a gold-colored front panel with a small white label on the left and a small white label on the right. The background is a plain, light-colored surface.

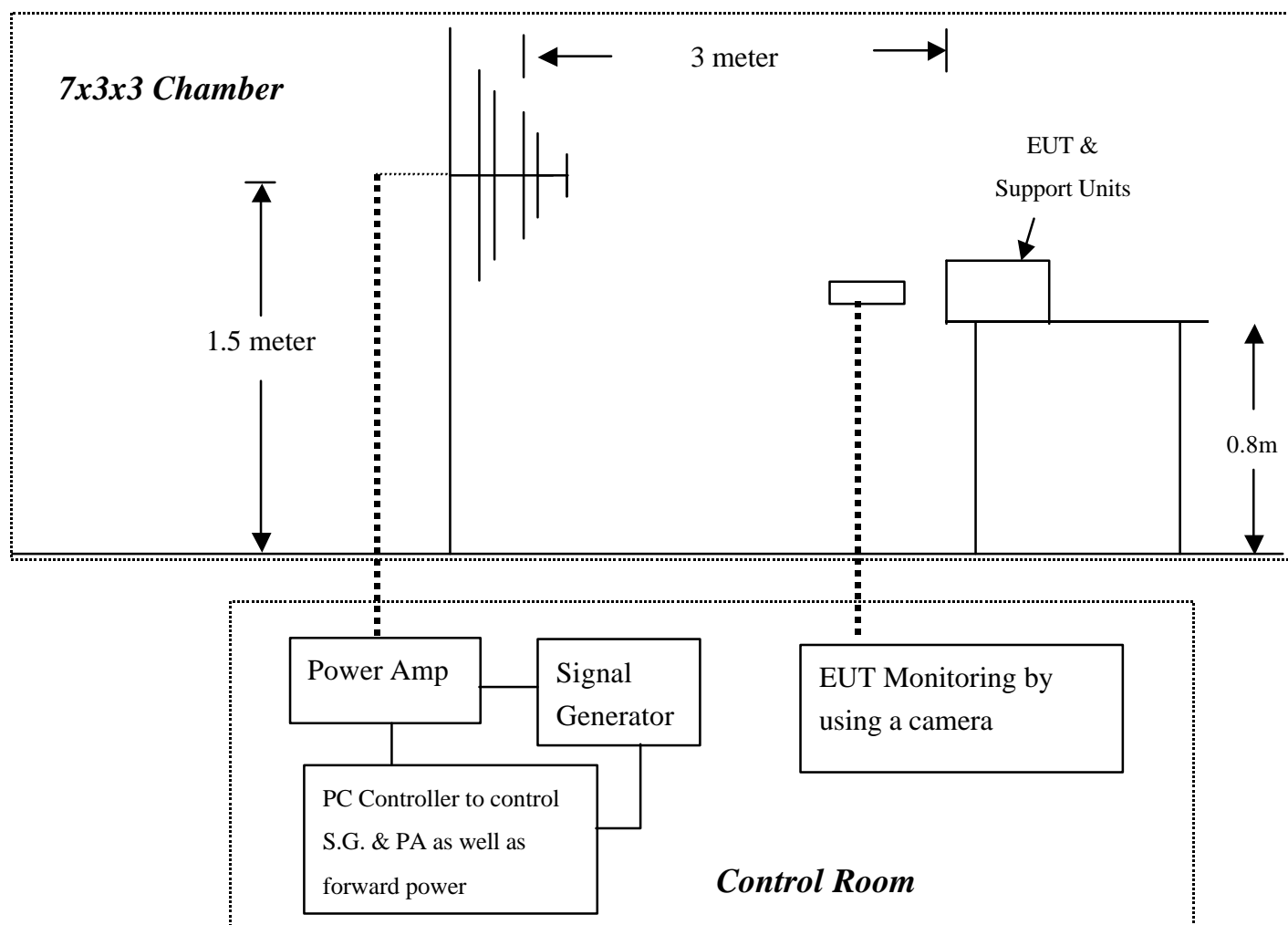
A gold-colored industrial power supply unit (PSU) is shown against a light green background. The unit is rectangular and features a front-loading drive bay on the left side. To the right of the drive bay is a power input socket. The unit is secured with four screws, each marked with a blue cross. A small white label is visible on the top right corner of the unit.

14 SECTION 4 IEC 61000-4-3 (RADIATED ELECTROMAGNETIC FIELD)

RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST

Port	: Enclosure
Basic Standard	: IEC 61000-4-3
Requirements	: 10 V/m / with 80% AM. 1kHz Modulation. (Customer requested)
Performance Criteria	: A (Standard require)
Tester	: Sam Chang
Temperature	: 20°C
Humidity	: 49%
Pressure	: 1006mbar

Block Diagram of Test Setup:



Test Procedure:

1. The EUT was located at the edge of supporting table keep 3 meter away from transmitting antenna, it just the calibrated square area of field uniformity. The support units were located outside of the uniformity area, but the cable(s) connected with EUT were exposed to the calibrated field as per IEC 61000-4-3.
2. The LAN communication software was loaded and executed on PC system.
3. Adjusting the monitoring camera to monitor the 'H' message as clear as possible.
4. Setting the testing parameters of RS test software per IEC 61000-4-3.
5. Performing the test at each side of with specified level from 80MHz to 1000MHz at 1% steps.
6. Recording the test result in following table.
7. It is not necessary to perform test as per annex A of EN 55024 if the EUT doesn't belong to ITE product.

IEC 61000-4-3 test conditions:

Test level : 10V/m

Steps : 1 % of fundamental

Dwell Time : 3 sec

Range (MHz)	Field	Modulation	Polarity	Position (°)	Result (Pass/Fail)
80-1000	10V	Yes	H	Front	Pass
80-1000	10V	Yes	V	Front	Pass
80-1000	10V	Yes	H	Right	Pass
80-1000	10V	Yes	V	Right	Pass
80-1000	10V	Yes	H	Back	Pass
80-1000	10V	Yes	V	Back	Pass
80-1000	10V	Yes	H	Left	Pass
80-1000	10V	Yes	V	Left	Pass

Performance & Result:

- ☒ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self-recoverable or can be restored by the operation of controls.

☒ **PASS**

☐ **FAILED**

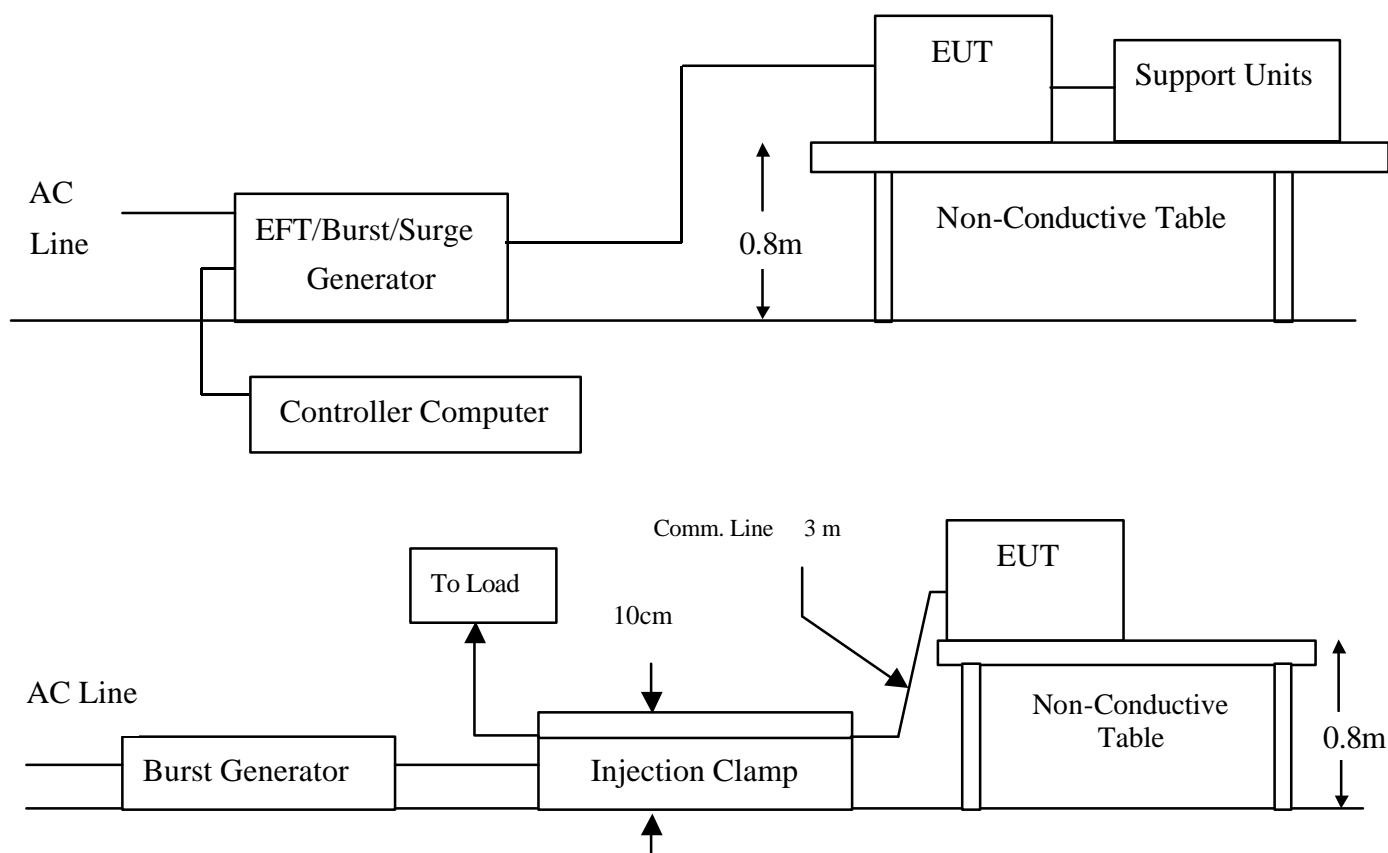
Observation: No any function degraded during the tests.

15 SECTION 5 IEC 61000-4-4 (FAST TRANSIENTS/BURST)

FAST TRANSIENTS/BURST IMMUNITY TEST

Port	: On Power Supply Lines and Data Lines
Basic Standard	: IEC 61000-4-4
Requirements	: ± 1 kV for Power Supply Line ± 0.5 kV to LAN Cable
Performance Criteria	: B (Standard require)
Tester	: Tommy Lin
Temperature	: 22°C
Humidity	: 50%
Pressure	: 1008mbar

Block Diagram of Test Setup:



Test Procedure:

1. The EUT and support units were located on a wooden table 0.8 m away from ground reference plane.
2. A 1.0 meter long power cord was attached to EUT during the test.
3. The length of communication cable between communication port and clamp was keeping within 1 meter.
4. A test program was loaded and executed in Windows mode.
5. The data was sent to the screen of monitor and filling the screens with upper case of "H" patterns.
6. The test program exercised related support units sequentially.
7. Repeating step 3 to 6 through the test and increase test voltage to the EUT ports from minimum to standard request or client request.
8. Recording the test result as shown in following table.

Test conditions:

Impulse Frequency : 5kHz

Tr/Th : 5/50ns

Burst Duration : 15ms

Burst Period : 3Hz

Inject Line	Voltage kV	Inject Method	Result (Pass/Fail)
L1	± 1	Direct	Pass
N	± 1	Direct	Pass
PE	± 1	Direct	Pass
L1 + N	± 1	Direct	Pass
L1 + PE	± 1	Direct	Pass
N + PE	± 1	Direct	Pass
L1 + N + PE	± 1	Direct	Pass
LAN Cable	± 0.5	Clamp	Pass

Performance & Result:

- ☒ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

☒ **PASS**

☐ **FAILED**

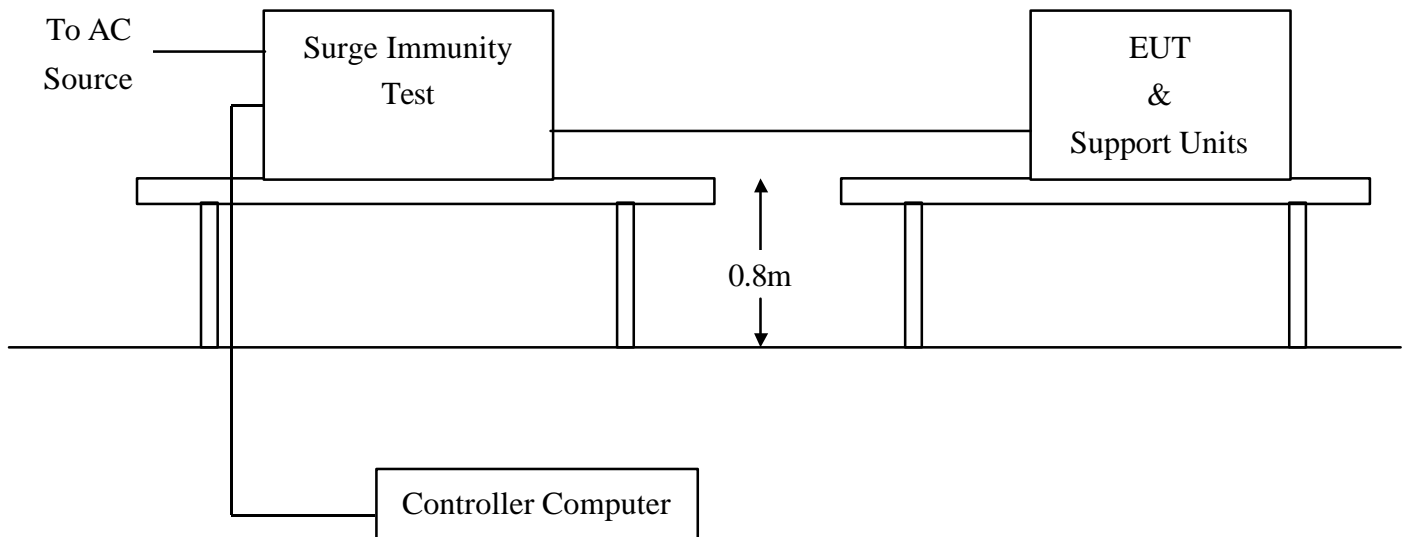
Observation: No any function degraded during the tests.

16 SECTION 6 IEC 61000-4-5 (SURGE IMMUNITY)

SURGE IMMUNITY TEST

Port : Power Cord
Basic Standard : IEC 61000-4-5
Requirements : ± 1 kV (Line to Line)
 ± 2 kV (Line to Ground)
Performance Criteria : B (Standard require)
Tester : Tommy Lin
Temperature : 22°C
Humidity : 50%
Pressure : 1008mbar

Block Diagram of Test Setup:



Test Procedure:

1. The EUT and support units were located on a wooden table 0.8 m away from ground floor.
2. A test program was loaded and executed in Windows mode.
3. The data was sent to the screen of monitor and filling the screens with upper case of "H" patterns.
4. The test program exercised related support units sequentially.
5. Repeating step 3 to 4 through the test and increase test voltage to the EUT ports from minimum to standard request or client request.
6. Recording the test result as shown in following table.

Test conditions:

Voltage Waveform : 1.2/50 *us*
 Current Waveform : 8/20 *us*
 Polarity : Positive/Negative
 Phase angle : 0°, 90°, 270°
 Number of Test : 5

Coupling Line	Voltage (kV)	Polarity	Coupling Method	Result (Pass/Fail)
L1-L2	1	Positive	Capacitive	Pass
L1-PE	2	Positive	Capacitive	Pass
L2-PE	2	Positive	Capacitive	Pass
L1-L2	1	Negative	Capacitive	Pass
L1-PE	2	Negative	Capacitive	Pass
L2-PE	2	Negative	Capacitive	Pass

Performance & Result:

- ☒ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

<input checked="" type="checkbox"/> PASS <input type="checkbox"/> FAILED
Observation: No any function degraded during the tests.

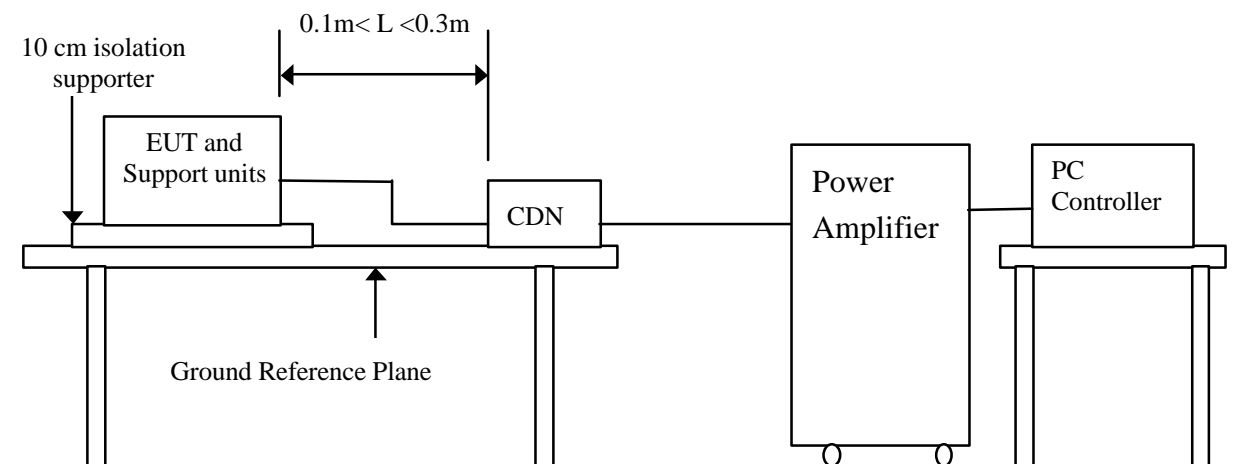
17 SECTION 7 IEC 61000-4-6 (CONDUCTED DISTRBANCE/INDUCED RADIO-FREQUENCY FIELD)

CONDUCTED DISTRBANCE/INDUCED RADIO-FREQUENCY FIELD IMMUNITY TEST

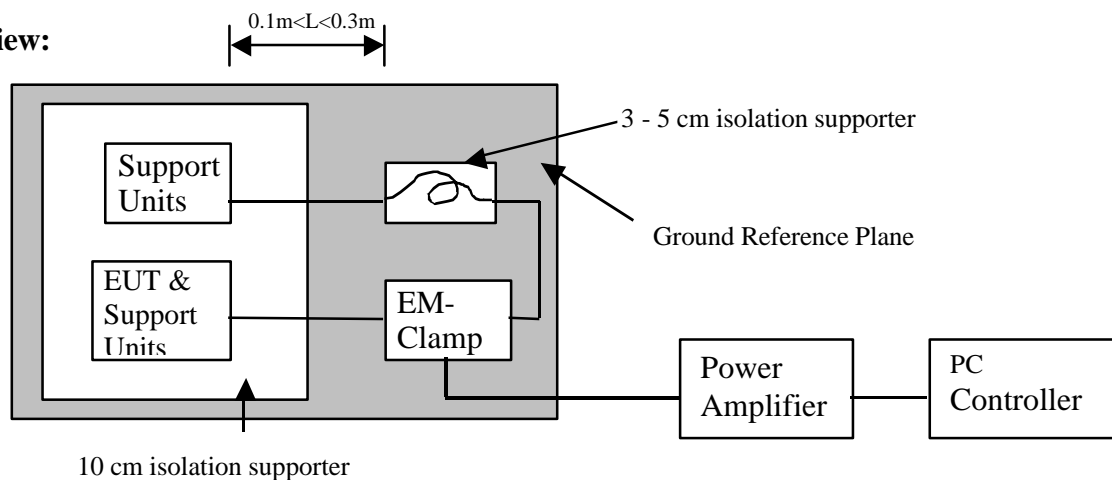
Port	: AC Port and LAN Cable
Basic Standard	: IEC 61000-4-6
Requirements	: 10V with modulated (Customer requested)
Injection Method	: CDN-M3 for Power Cord EM-Clamp for LAN Cable
Performance Criteria	: A (Standard require)
Tester	: Tommy Lin
Temperature	: 22°C
Humidity	: 50%
Pressure	: 1008mbar

Block Diagram of Test Setup:

Side View:



Top view:



Test Procedure:

1. The EUT and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.
2. A 'H' messages were displayed on screen of monitor via EUT.
3. Adjusting the monitoring camera to monitor the 'H' message as clear as possible.
4. Setting the testing parameters of CS test software per IEC 61000-4-6.
5. Recording the test result in following table.

Test conditions:

Frequency Range : 0.15MHz-80MHz

Frequency Step : 1% of fundamental

Dwell Time : 3 sec

Range (MHz)	Field	Modulation	Result (Pass/Fail)
0.15-80	10V	Yes	Pass

Performance & Result:

- ☒ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self-recoverable or can be restored by the operation of controls.

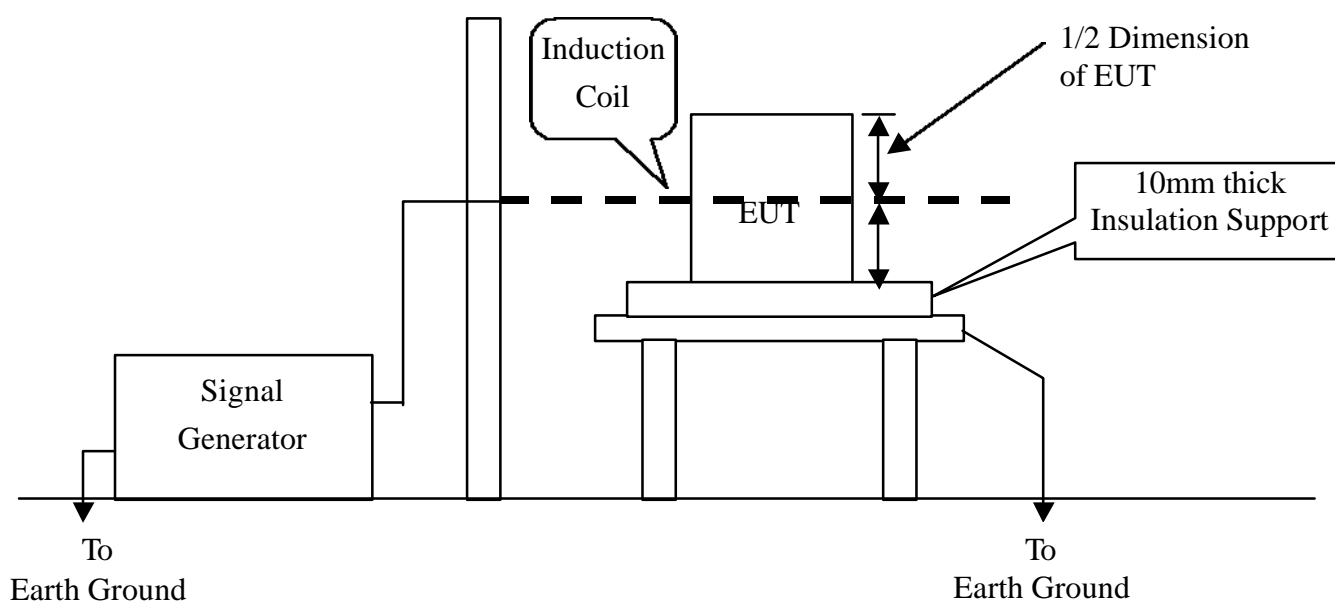
<input checked="" type="checkbox"/> PASS <input type="checkbox"/> FAILED
Observation: No any function degraded during the tests.

18 SECTION 8 IEC 61000-4-8 (POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST)

POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST

Port	: Enclosure
Basic Standard	: IEC 61000-4-8
Requirements	: 30 A/m (Customer requested)
Performance Criteria	: A (Standard Required)
Tester	: Tommy Lin
Temperature	: 22°C
Humidity	: 50%
Pressure	: 1008mbar

Block Diagram of Test Setup:



Test Procedure:

1. The EUT and support units were located on Ground Reference Plane with the interposition of a 0.1 m thickness insulation support.
2. Putting the induction coil on horizontal direction.(X direction)
3. A test program was loaded and executed in Windows mode.
4. The data was sent to the screen of monitor and filling the screen with upper case of "H" patterns.
5. The test program exercised related support units sequentially.
6. Repeating step 3 to 5 through the test.
7. Recording the test result as shown in following table.
8. Rotating the induction coil by 90° (Y direction) then repeat step 3 to 7.
9. Rotating the induction coil by 90° again (Z direction) then repeat step 3 to 7.

*. Test conditions:

Field Strength : 30A/m
Power Freq. : 50Hz
Orientation : X, Y, Z

Orientation	Field	Result (Pass/Fail)	Remark
X	30 A	Pass	
Y	30 A	Pass	
Z	30 A	Pass	

Performance & Result:

- ☒ **Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- ☐ **Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- ☐ **Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

☒ **PASS**

☐ **FAILED**

Observation: No any function degraded during the tests.

19 SECTION 9 IEC 61000-4-11 (VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS)

VOLTAGE DIPS / SHORT INTERRUPTIONS

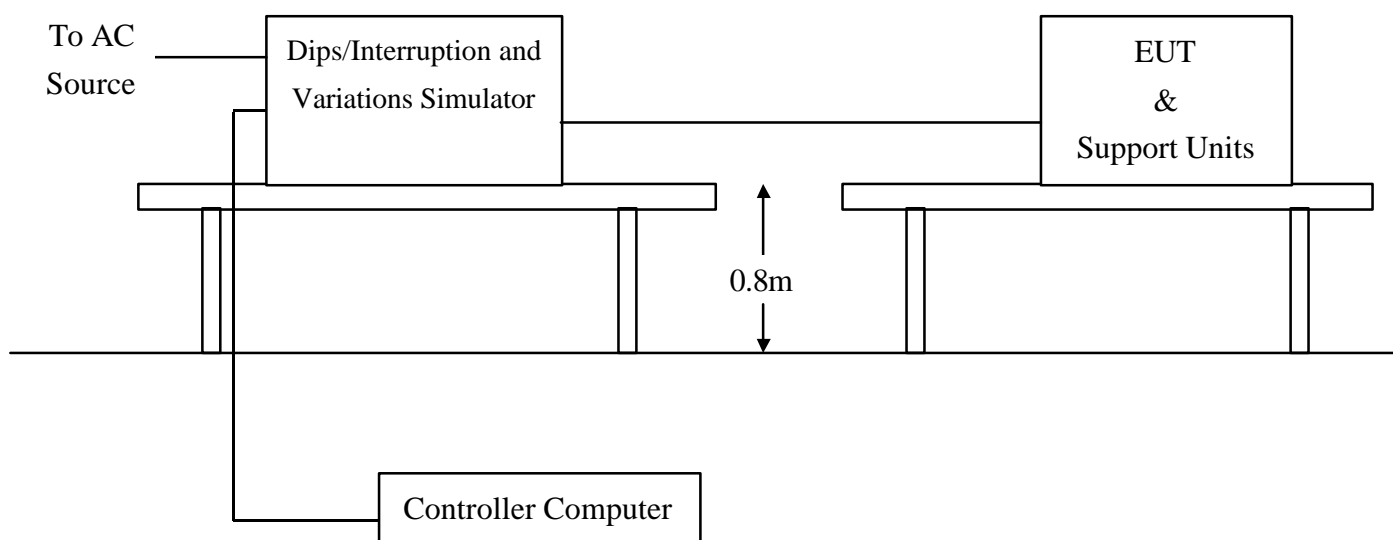
Port : AC mains
Basic Standard : IEC 61000-4-11 (1994)
Requirement : PHASE ANGLE 0, 45, 90, 135, 180, 225, 270, 315 degrees

Voltage Dips	Test Level % U_T	Reduction (%)	Duration (Periods)	Performance Criteria
	<5	>95	0.5	B
	70	30	25	C

Voltage Interceptions	Test Level % U_T	Reduction (%)	Duration (Periods)	Performance Criteria
	<5	>95	250	C

Test Interval : Min. 10 sec.
Tester : Tommy Lin
Temperature : 22°C
Humidity : 50%
Pressure : 1008mbar

Block Diagram of Test Setup:



Test Procedure:

1. The EUT and support units were located on a wooden table, 0.8 m away from ground floor.
2. A test program was loaded and executed in Windows mode.
3. The data was sent to the screen of monitor and filling the screens with upper case of "H" patterns.
4. The test program exercised related support units sequentially.
5. Setting the parameter of tests and then Perform the test software of test simulator.
6. Conditions changes to occur at 0 degree crossover point of the voltage waveform.
7. Repeating step 3 to 4 through the test.
8. Recording the test result in test record form.

Test conditions:

The duration with a sequence of three dips/interruptions with interval of 10 s minimum
(Between each test event)

Voltage Dips:

Test Level % U_T	Reduction (%)	Duration (Periods)	Observation	Meet Performance Criteria
0	100	0.5	Normal	A
70	30	25	Normal	A

Voltage Interruptions:

Test Level % U_T	Reduction (%)	Duration (Periods)	Observation	Meet Performance Criteria
0	100	250	EUT shut down but can be recovered by manual, as the events disappear.	C

Normal: No any functions degrade during and after the test.

Performance & Result:

Criteria A: The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.

Criteria B: The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.

Criteria C: Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.



PASS



FAILED

20 APPENDIX 1 PHOTOGRAPHS OF TEST SETUP

20.1 LINE CONDUCTED EMISSION TEST (EN 55022)

Front View



Back view



20.2 COMMON MODE CONDUCTED EMISSION TEST



20.3 RADIATED EMISSION TEST (EN 55022)

Front View



Back view



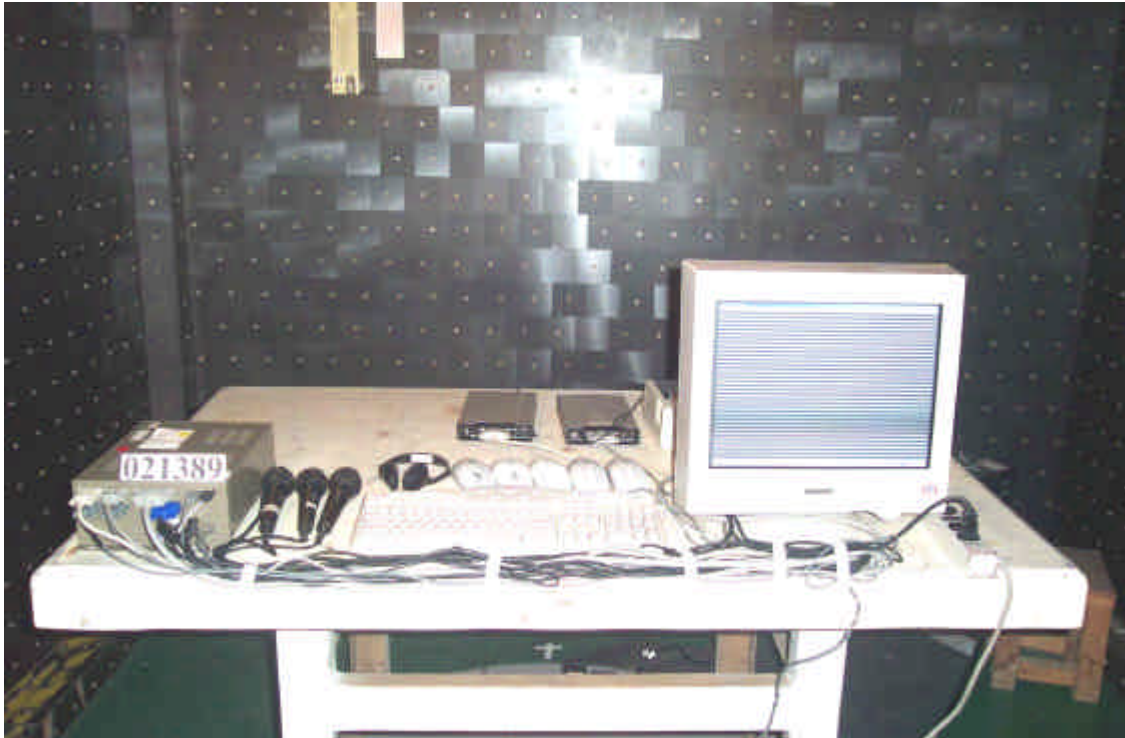
20.4 POWER HARMONIC & VOLTAGE FLUCTUATION / FLICKER TEST (EN 61000-3-2, EN 61000-3-3)



20.5 ELECTROSTATIC DISCHARGE TEST (IEC 61000-4-2)



20.6 RADIATED ELECTROMAGNETIC FIELD (IEC 61000-4-3)



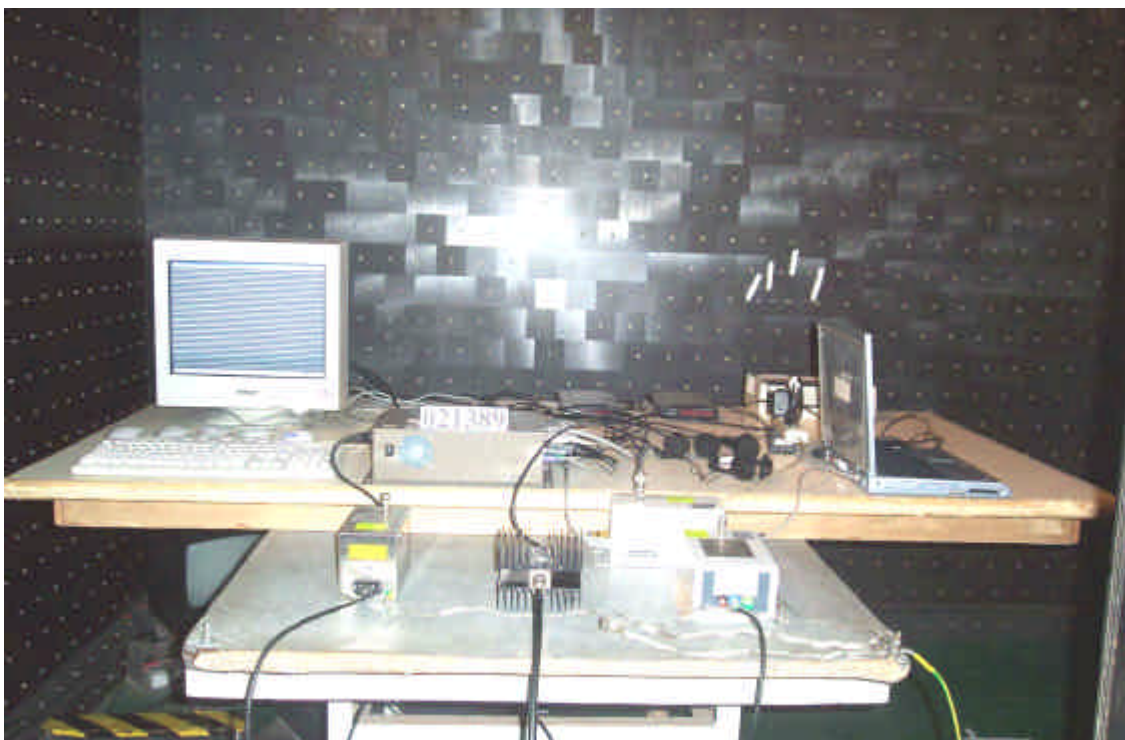
20.7 FAST TRANSIENTS/BURST TEST (IEC 61000-4-4)



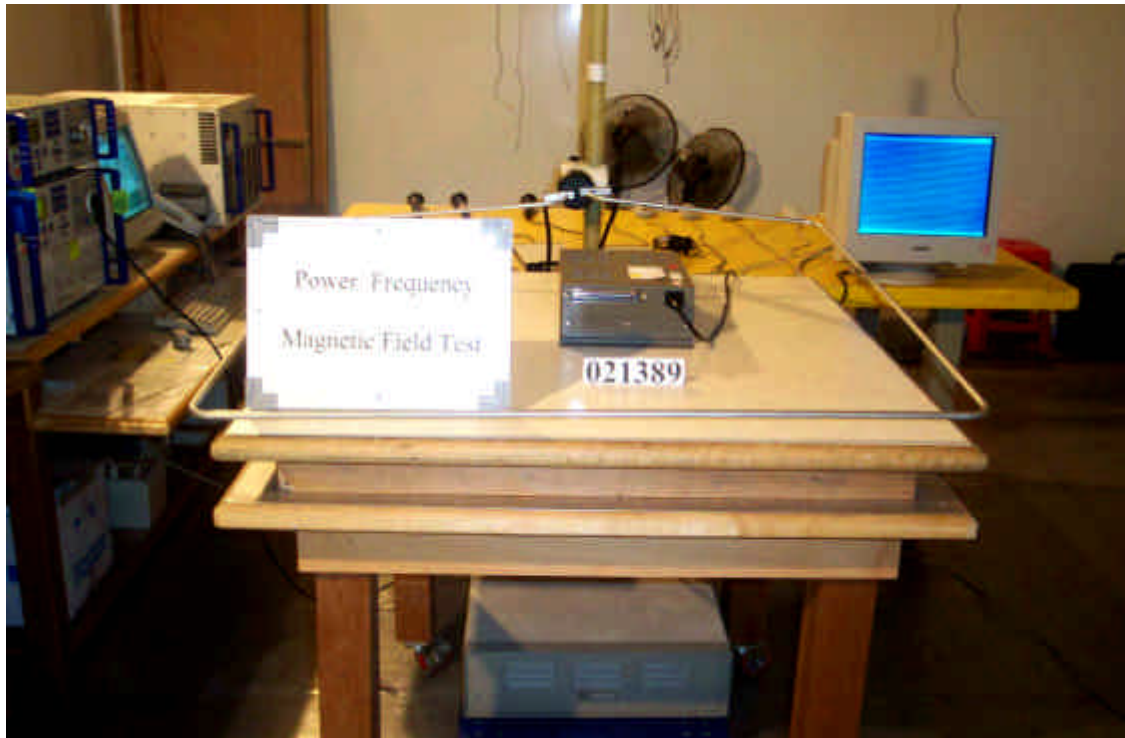
20.8 SURGE IMMUNITY TEST (IEC 61000-4-5)



20.9 CONDUCTED DISTURBANCE, INDUCED BY RADIO-FREQUENCY FIELDS TEST (IEC 61000-4-6)



20.10 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST (IEC 61000-4-8)



20.11 VOLTAGE DIPS / INTERRUPTION TEST (IEC 61000-4-11)



21 APPENDIX 2 PHOTOGRAPHS OF EUT

Front View of EUT



Back View of EUT



Right View of EUT



Left View of EUT



Bottom View of EUT



View of EUT (MBPC-4000-9575)



View of EUT (MBPC-4000-9577)

